

TEST REPORT

Applicant: Hytera Communications Corporation Limited

Address: Hytera Tower, Hi-Tech Industrial Park North, 9108# Beihuan Road, Nanshan District, Shenzhen, P.R.C., P 518057

Product Name: Two-way Radio (S1mini)

Model Name: HYT-S10

Type of Equipment: Certification Ordinance Article 2-1-19

Test method(s): MIC Notice No.88 of 2004, Appendix No.43

Report Number: 2602S01344E-RF-07A

Report Date: 2026/5/28

The above device has been tested and found compliant with the requirement of the relevant standards by Bay Area Compliance Laboratories Corp. (Dongguan).

Carlos Wu

Rocky Xiao

Reviewed By: Carlos Wu

Approved By: Rocky Xiao

Title: Project Engineer

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1 - DOCUMENT REVISION HISTORY

Revision Number	Report Number	Description of Revision	Date of Revision
1.0	2602S01344E-RF-07A	Original Report	2026/5/28

2 - SUMMARY OF TEST RESULTS

Rules and clauses	Description of Test	Result
OR: Article 5, Annex 1.7&8	Frequency Tolerance	Compliant
OR: Article 6, Annex 2.30	Occupied Bandwidth	Compliant
OR: Article 7, Annex 3.26	Unwanted Emission strength	Compliant
OR: Article 49-20, Article 14.7	Antenna Output Power and Tolerance	Compliant
OR: Article 24.2	Secondary Radiated Emission Strength	Compliant
OR: Article 49-20	Carrier sense capability (1)	Not Applicable*
	Carrier sense capability (2)	Not Applicable**
	Carrier sense capability (3)	Not Applicable***
OR: Article 49-20	Transmission frequency channel switching function	Not Applicable*
OR: Article 49-20	Transmission Antenna Gain	Not Applicable****
OR: Article 49-20	Transmission Radiation Angle Width	Not Applicable****
OR: Article 49-20	Frequency Hopping Dwell Time	Not Applicable*****
OR: Article 9.4(8) RE: Article 6.2(3) Notice No.424	Interference Prevention Function	Compliant
OR: Article 49-20	Construction Protection Confirmation	Compliant

Note:

Not Applicable*: Only required for device with “compensating for the reduction of EIRP with output power” function.

Not Applicable**: Only required for OBW between 26MHz and 40MHz with OFDM modulation type.

Not Applicable***: Only required for outdoor use radio control of model airplanes.

Not Applicable****: This item not applicable when the EIRP less than the limit.

Not Applicable*****: Testing is only required for FHSS system devices.

OR: Ordinance Regulating radio equipment (November 30, 1950, Radio Regulatory Commission Regulations No.18)

RE: Regulations for Enforcement of the radio law (November 30, 1950, Radio Regulatory Commission Regulations No.14)

Notice No.424: MIC Notice No.424, 1994.

3 - GENERAL INFORMATION

3.1 Product Description for Equipment Under Test (EUT)

Product Name:	Two-way Radio (S1mini)
Test Model:	HYT-S10
Rated Input Voltage:	DC 3.85V from battery
Serial Number:	3KEN-1
EUT Received Date:	2026/4/20
EUT Received Status:	Good

3.2 Accessory Information

Accessory Description	Manufacturer	Model	Parameters
Adapter	Hytera	S010WT0500200	Input: 100-240Vac~50/60Hz,400mA Output: 5.0Vdc,2000mA

3.3 Technical Specification

Operation Frequency Range (MHz):	2402-2480
Max. RF Output Power (Conducted, mW):	BLE 1M: 2.5 BLE 2M: 2.5
Number of TX Chain(s):	1
Number of RX Chain(s):	1
Antenna Gain (dBi)▲:	0.69
Modulation Type:	GFSK
Emission Type	F1D

3.4 Test Facility

The Test site used by Bay Area Compliance Laboratories Corp. (Dongguan) to collect test data is located on the No.12, Pulong East 1st Road, Tangxia Town, Dongguan, Guangdong, China.

3.5 Measurement Uncertainty

Parameter	Measurement Uncertainty
Frequency Error	±0.076 ppm
Occupied Channel Bandwidth	±5 %
RF output power, conducted	±0.55dB
Unwanted Emissions, conducted	±2.47 dB
Temperature	±1 °C
Humidity	±5%
DC and low frequency voltages	±0.4%
Duty Cycle	1%

Note: Otherwise required by the applicant or Product Regulations, Decision Rule in this report did not consider the uncertainty. The extended uncertainty given in this report is obtained by combining the standard uncertainty times the coverage factor K with the 95% confidence interval.

4 - DESCRIPTION OF TEST CONFIGURATION

4.1 Operation Frequency Detail

The system was configured for testing in engineering mode, which was provided by manufacturer. 40 channels are provided as below table:

Channel	Frequency (MHz)	Channel	Frequency (MHz)
0	2402	20	2442
1	2404	...	...
...	...	...	...
...	...	...	...
...	...	38	2478
19	2440	39	2480

For lowest, middle and highest channel, EUT was tested with channel 0, 19 and 39.

The extreme voltage test conditions which were declared by the manufacturer and the normal conditions are as below:

NV: Normal Voltage 3.85V_{DC}

LV: Low Voltage 3.465V_{DC}

HV: High Voltage 4.235V_{DC}

4.2 EUT Operation Condition

The EUT was configured for testing in Engineering Mode, which was provided by the manufacturer. The EUT configuration as below:

EUT Exercise Software: sscom5.13.1.exe			
The software was provided by manufacturer. The maximum power was configured as below, that was provided by the manufacturer [▲] :			
Mode	Power Level Setting		
	Lowest Channel	Middle Channel	Highest Channel
BLE_1M	15	15	15
BLE_2M	15	15	15

4.3 Equipment Modifications

No modifications are made to the EUT during all test items.

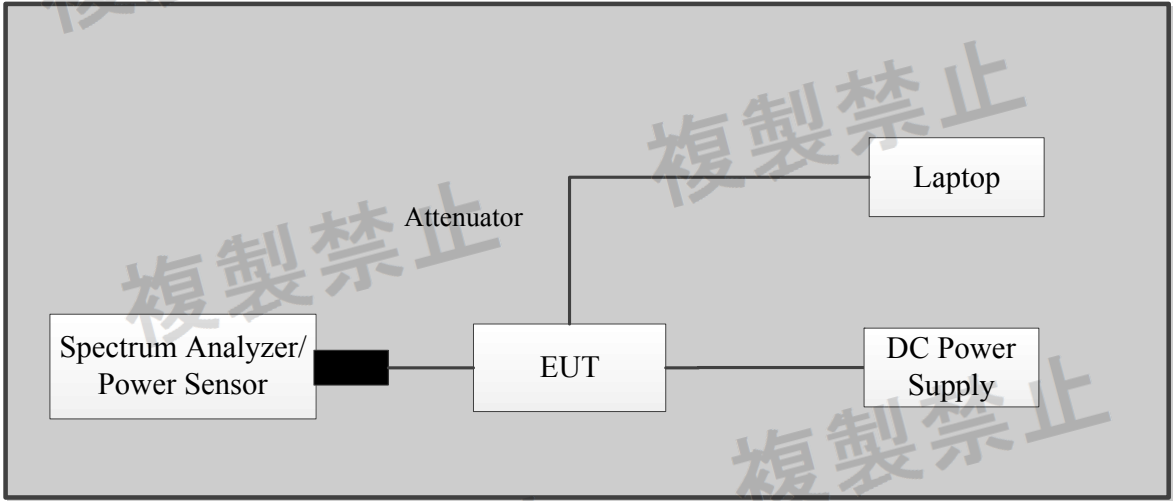
4.4 Support Equipment List and Details

Manufacturer	Description	Model	Serial Number
DELL	Laptop	E6410ATG	EMZBPC21103005

4.5 Support Cable List and Details

Cable Description	Shielding Type	Ferrite Core	Length (m)	From Port	To
DC Power Cable	No	No	0.8	DC power Supply	EUT
USB Cable	No	No	1	Laptop	EUT

4.6 Typical Configuration for Test Setup



5 - REQUIREMENTS AND TEST PROCEDURES

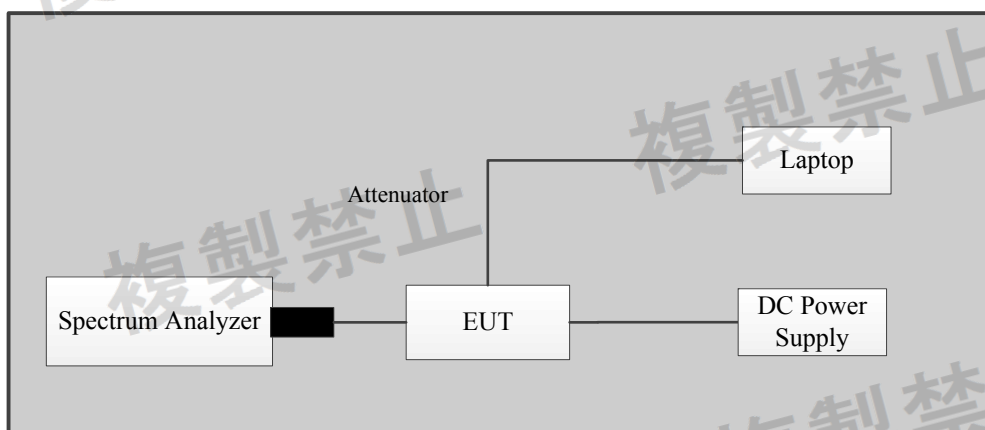
5.1 Frequency Tolerance

5.1.1 Requirements

OR: Article 5, Annex 1.7&8: Within ± 50 ppm.

5.1.2 Test setup block diagram

5.1.3 Test Condition



Voltage Test Condition	LV
	NV
	HV

5.1.4 Test Procedure

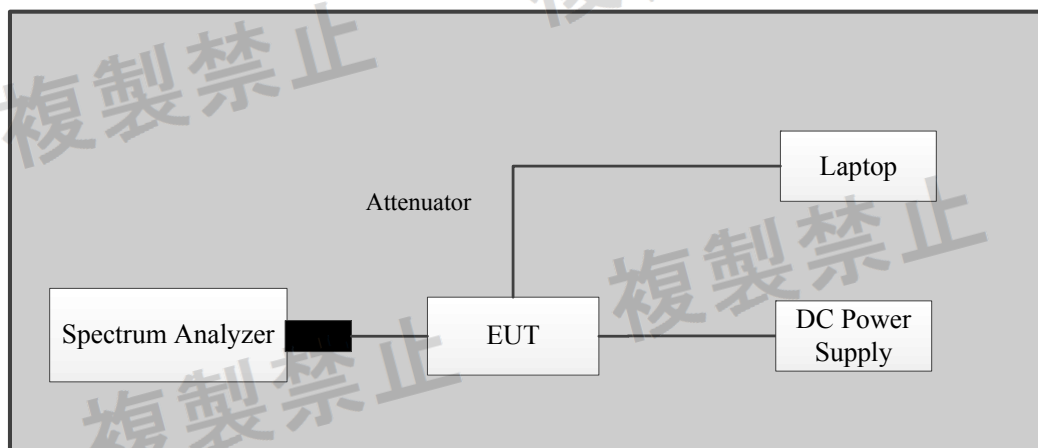
- Set the EUT working in voltage NV;
 - in the case of unmodulated waves (continuous or continuous bursts), measure directly with a frequency meter.
 - in the case of burst waves, the time to obtain sufficient accuracy is measured, and the average value is calculated as the measured value.
 - in the case of a test mode that produces a characteristic frequency spectrum, measured with a spectrum analyzer. Measure the 10dBc center frequency.
- Record the test result.
- Repeat the test for LV and HV if the product lacks a sufficiently effective voltage regulation circuit.

5.2 Occupied Bandwidth

5.2.1 Requirements

OR: Article 6, Annex 2.30: within 26MHz

5.2.2 Test setup block diagram



5.2.3 Test Condition

Voltage Test Condition	LV
	NV
	HV

5.2.4 Test Procedure

- Set the EUT working in voltage NV;
 - Set the spectrum analyzer as shown in “SA Setting”.
 - After repeating the sweep until no further changes are observed in the display, load all data point values into an array variable on the computer.
 - Convert the dB values for all data points to real numbers in power dimensions.
 - Calculate the total power sum for all data points and designate it as “Total Power”.
 - Add power sequentially upward starting from the lowest frequency data point until the sum reaches 0.5% of the “Total Power.” Calculate the limit data point at this value. Convert this limit point to frequency and designate it as the “Lower Limit Frequency.”
 - Starting from the data point with the highest frequency, add power sequentially downward to calculate the limit data point where this value reaches 0.5% of the “Total Power”. Convert this limit point to frequency and designate it as the “Upper Limit Frequency”.
- Record the test result.
- Repeat the test for LV and HV if the product lacks a sufficiently effective voltage regulation circuit.

SA Setting:

Center Frequency: Test Frequency

Sweep Frequency Bandwidth: Approximately 2 to 3.5 times the allowable value

Resolution Bandwidth: 3% or less of the allowable value

Video Bandwidth: Similar to the resolution bandwidth

Input Level: Level at which the carrier level can be measured without being affected by the spectrum analyzer's noise level

Sweep time: Minimum time to guarantee measurement accuracy
(For burst waves, time allowing at least one burst per sample)

Sweep mode: Continuous sweep

Detection mode: Positive peak (Note)

Display mode: Max hold (Note)

Note: For non-burst waves in orthogonal frequency division multiplexing (OFDM), the following applies:

Number of averaging cycles: 10 or more

Detection mode: Sample

5.3 Unwanted emission Strength

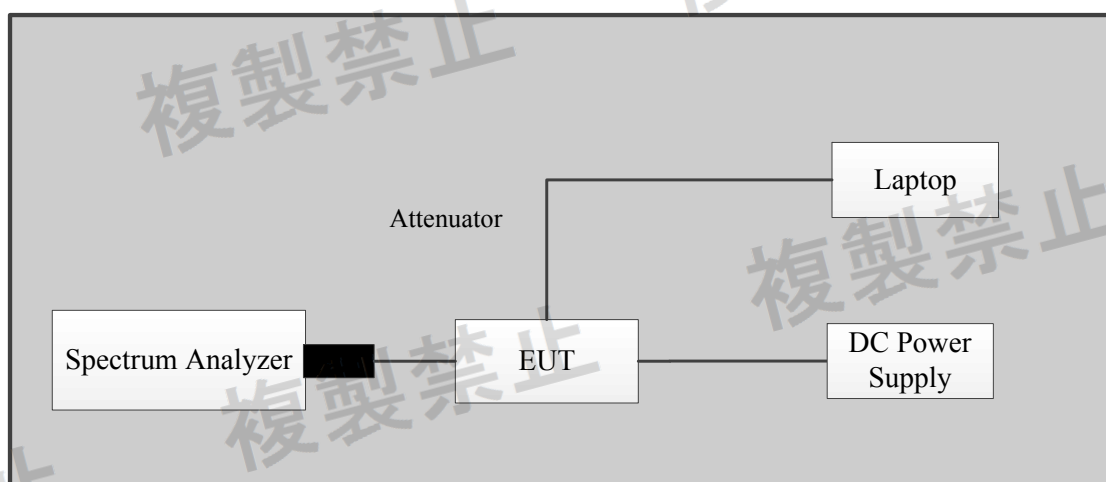
5.3.1 Requirements

OR: Article 7, Annex 3.26:

Frequency Band	Measurement Bandwidth	Limit
30M - 1000MHz	100kHz	$\leq 2.5\mu\text{W}/\text{MHz}$ ($0.25\mu\text{W}/100\text{kHz}$)*
100M - 2387MHz	1MHz	$\leq 2.5\mu\text{W}/\text{MHz}$
2387MHz - 2400MHz	1MHz	$\leq 25\mu\text{W}/\text{MHz}$
2483.5MHz - 2496.5MHz	1MHz	$\leq 25\mu\text{W}/\text{MHz}$
2496.5MHz - 12.5GHz	1MHz	$\leq 2.5\mu\text{W}/\text{MHz}$

Note: A factor 1/10 was times to the limit when the Measurement Bandwidth is 1/10 the RB in limit unit.

5.3.2 Test setup block diagram



5.3.3 Test Condition

Voltage Test Condition	LV
	NV
	HV

5.3.4 Test Procedure

a) Set the EUT working in voltage NV;

(1) Set the spectrum analyzer to “Step 1”, sweep the frequency, and search for unwanted emissions.

If the amplitude value of the detected unwanted emission does not satisfy the permissible intensity value for unwanted emissions specified in Appendix Table 3 of the Equipment Regulations, sequentially narrow the sweep frequency bandwidth to improve the spectrum analyzer's frequency accuracy and precisely determine the frequency of that unwanted emission.

However, if it is clear from the amplitude value of the detected unwanted emission that it satisfies the permissible intensity value, measurement “Step 2” is not performed.

(2) Set the spectrum analyzer to “Step 2” and determine the amplitude value of the unwanted emission.

(3) Near the carrier frequency, etc., the resolution bandwidth may be set narrower as necessary for measurement. In such cases, convert the unwanted emission intensity to a value in the reference bandwidth.

- b) Record the test result.
- c) Repeat the test for LV and HV if the product lacks a sufficiently effective voltage regulation circuit.

Where the Spectrum analyzer setting as following:

Step 1:

Sweep Frequency Width: Spurious region
Resolution Bandwidth: Reference bandwidth
Video Bandwidth: Approximately equal to resolution bandwidth
Sweep Time: Minimum time to guarantee measurement accuracy
Y-axis Scale: 10 dB/Div
Input Level: Value providing maximum dynamic range
Sweep Mode: Single sweep
Detection Mode: Positive Peak

Step 2:

Center Frequency: Frequency of the carrier wave or detected spurious emission
Sweep Frequency Width: 0 Hz
Resolution Bandwidth: Reference Bandwidth
Video Bandwidth: Approximately 3 times the resolution bandwidth
Y-axis Scale: 10 dB/Div
Input Level: Value for maximum dynamic range
Sweep Mode: Single sweep
Detection Mode: Sample

5.4 Antenna Output power and Tolerance

5.4.1 Requirements

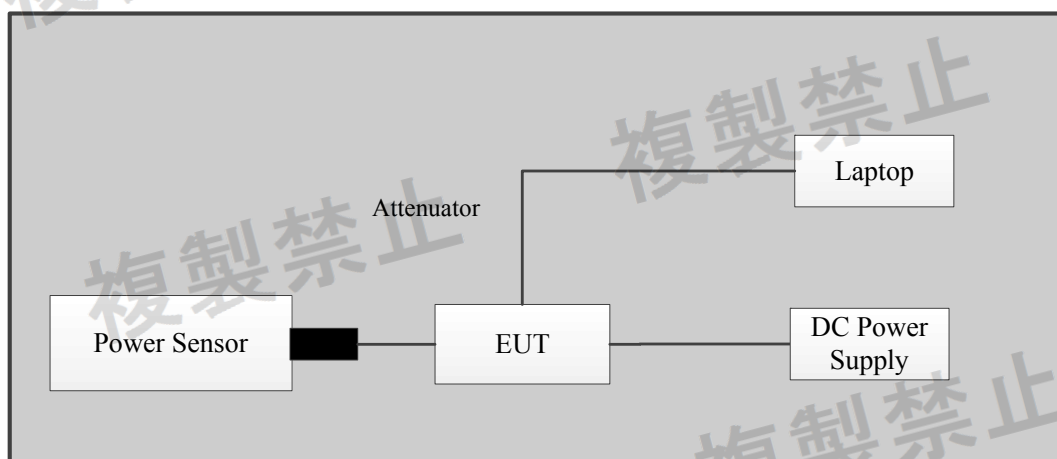
OR: Article 49-20, Article 14.7:

Output Power: 10mW or less

Output Power Tolerance: +20% ~ -80%

EIRP: 12.14dBm

5.4.2 Test setup block diagram



5.4.3 Test Condition

Voltage Test Condition	LV
	NV
	HV

5.4.4 Test Procedure

a) Set the EUT working in voltage NV;

(1) Connect the high-frequency power meter to the output of a dummy load (attenuator) and measure the total power.

(2) The antenna power shall be as follows:

(i) For continuous waves: The value in (a);

(ii) For burst waves: The value in (a) and the value calculated from the transmission duty cycle as the average power within the burst.

b) Record the test result.

c) Repeat the test for LV and HV if the product lacks a sufficiently effective voltage regulation circuit.

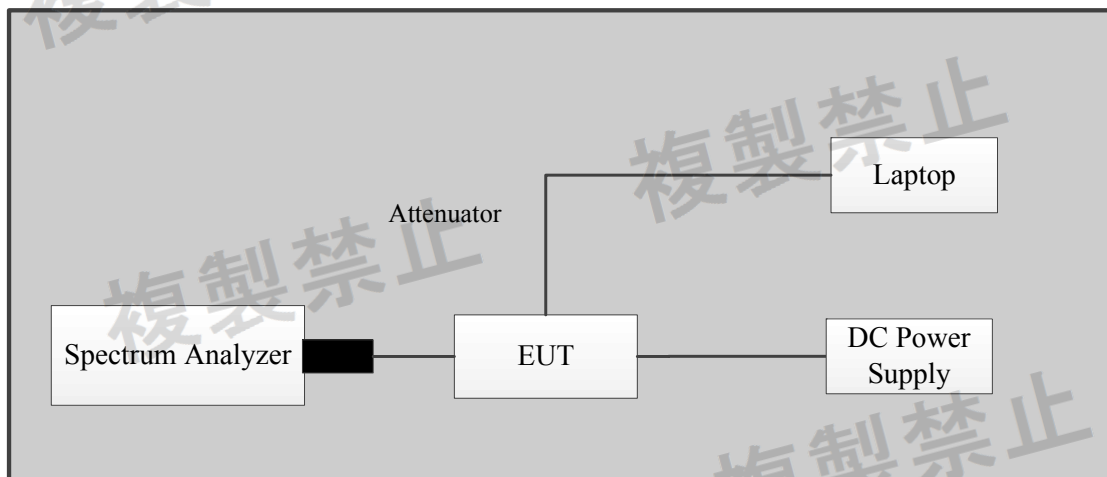
5.5 Secondary Radiated Emission Strength

5.5.1 Requirements

OR: Article 24.2:

Frequency Band	Measurement Bandwidth	Limit
30MHz-1000MHz	100kHz	$\leq 4 \text{ nW}$
1000MHz - 12.5GHz	1MHz	$\leq 20 \text{ nW}$

5.5.2 Test setup block diagram



5.5.3 Test Condition

Voltage Test Condition	LV
	NV
	HV

5.5.4 Test Procedure

- Set the EUT working in voltage NV;
 - Set the spectrum analyzer as shown in “Step 1” and search for the maximum amplitude of the spurious emission.
 - If the searched value is 1/10 or less of the allowable value, use the searched value as the measured value.
 - If the detected value exceeds 1/10 of the allowable value, sequentially narrow the frequency sweep width to approximately 10 times the resolution bandwidth to improve the center frequency setting accuracy of the spectrum analyzer. Measure the frequency of the spurious emission, set the spectrum analyzer as in “Step 2”, perform averaging processing, and measure the spurious emission power.
- Record the test result.
- Repeat the test for LV and HV if the product lacks a sufficiently effective voltage regulation circuit.

Where the Spectrum analyzer setting as following:

Step 1:

Sweep frequency bandwidth: 30 MHz or more, 12.5 GHz or less

Resolution bandwidth:

Frequencies below 1,000 MHz: 100 kHz

Frequencies at or above 1,000 MHz: 1 MHz

Video bandwidth: Similar to resolution bandwidth
Sweep time: Minimum time ensuring measurement accuracy
Y-axis scale: 10 dB/Div
Sweep mode: Single sweep
Detection Mode: Positive Peak

Step 2:

Center Frequency: The secondary emission frequency to be measured (the frequency detected)
Sweep Frequency Width: 0Hz
Resolution Bandwidth
 Frequency < 1,000MHz: 100kHz
 Frequency 1,000 MHz or higher: 1 MHz
Video Bandwidth: Similar to resolution bandwidth
Sweep Time: Minimum time to guarantee measurement accuracy
Y-axis Scale: 10 dB/Div
Sweep Mode: Single Sweep
Detection Mode: Sample

5.6 Interference Prevention Function

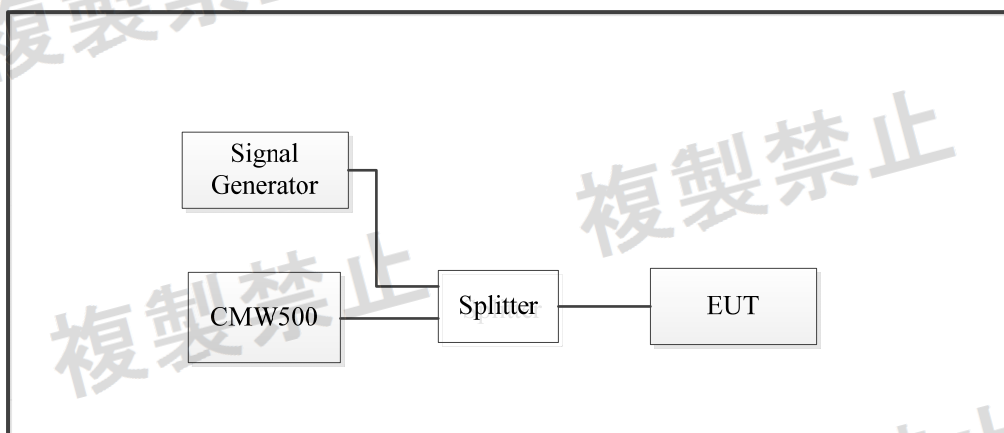
5.6.1 Requirements

OR: Article 9.4(8), RE: Article 6.2(3):

A wireless device used mainly in the same premises to automatically transmit or receive identification codes.

Article 1.8 of MPT Ministerial Notice No. 424 of 1994: 48 bits or more.

5.6.2 Test setup block diagram



5.6.3 Test Procedure

(1) When the test equipment has the capability to automatically transmit identification codes

- Transmit the identification code from the test equipment.
- Verify the transmitted identification code.

(2) When the test equipment has the capability to automatically receive identification codes

- Transmit the identification code from the counterpart device.
- Confirm that communication occurs with the test equipment.
- Transmit a code different from the counterpart device.
- Confirm that the test equipment either stops transmission or displays that the identification code is different.

6 - TEST DATA AND RESULTS

6.1 Frequency Error

Test Information:

Serial No.:	3KEN-1	Test Date:	2026/05/27
Test Site:	RF	Test Mode:	Transmitting
Tester:	Harper Shen	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	27.2	Relative Humidity: (%)	59	ATM Pressure: (kPa)	100.2
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Test Equipment List and Details:

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date	Calibration Agency	Calibration Method
R&S	Spectrum Analyzer	FSV40	101589	2025/07/28	2026/07/27	BACL Metrology	C
R&S	Coaxial Attenuator	10dB	F-08-EM512	2026/03/30	2027/03/29	BACL(DG)	D
JD	Test Software	JD Auto Test System	V1.0	N/A	N/A	N/A	N/A
All-sun	Clamp Meter	EM305A	8348897	2025/8/18	2026/8/17	BACL Metrology	C
Emerson	DC Power Supply	ONU4820	210213035320950100A0	N/A	N/A	N/A	N/A

* Statement of Traceability: Bay Area Compliance Laboratories Corp. (Dongguan) attests that all calibrations have been performed, traceable to National Primary Standards and International System of Units (SI).

Note:

- A. Calibration conducted by the National Institute of Information and Communications Technology (NICT) (hereinafter referred to as "NICT") or a designated calibration agency under Article 102-18 paragraph (1).
- B. Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Law (Law No. 51 of 1992).
- C. Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated calibration agency under Article 102-18 paragraph (1).
- D. Calibration conducted by using measuring instruments and other equipment which shall have been given any of calibration, etc. listed above from a) to c).

Test Condition: NV

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2402.00225	0.94	± 50	Pass
	2440	2440.00225	0.92		Pass
	2480	2480.00255	1.03		Pass

Test Condition: LV

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2401.99955	-0.19	± 50	Pass
	2440	2439.99955	-0.18		Pass
	2480	2479.99985	-0.06		Pass

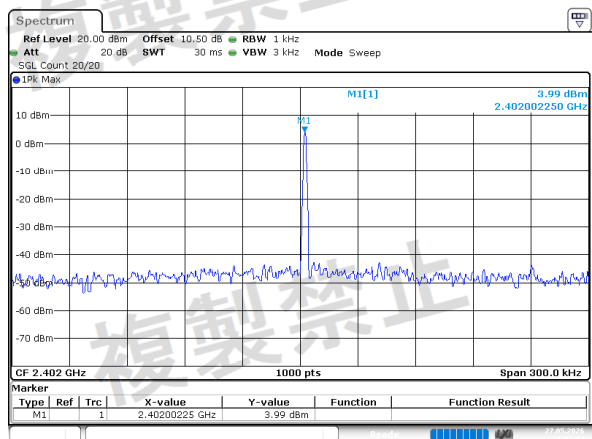
Test Condition: HV

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2402.00195	0.81	± 50	Pass
	2440	2440.00165	0.68		Pass
	2480	2480.00195	0.79		Pass

Frequency Tolerance = (Measure Frequency - Frequency)/Frequency*10⁶

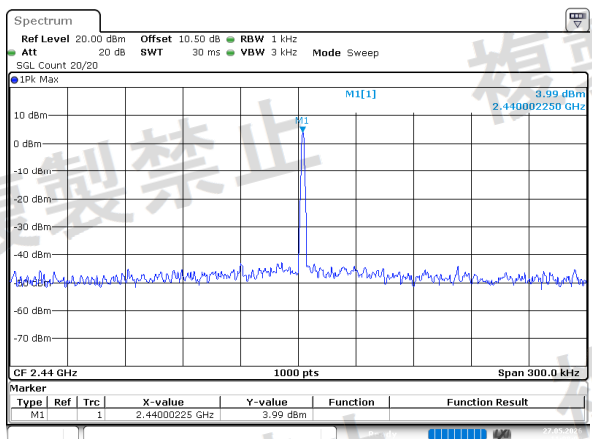
Test Condition: NV

2402MHz



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:07:34

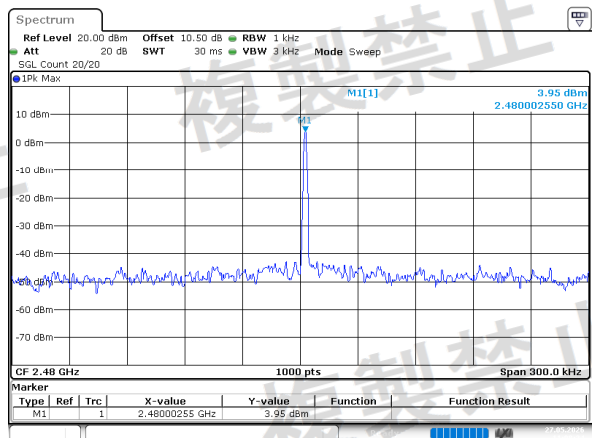
2440MHz



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:08:00

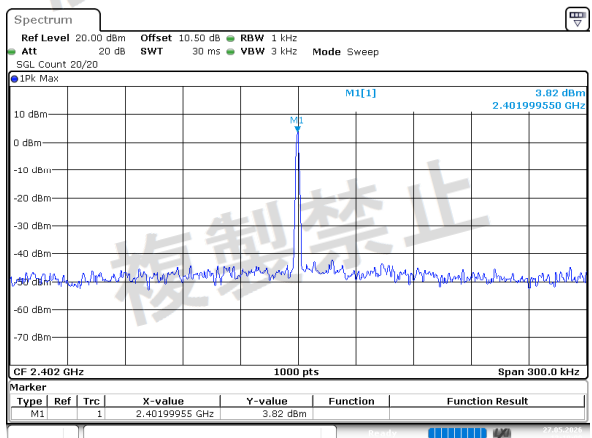
Test Condition: LV

2480MHz



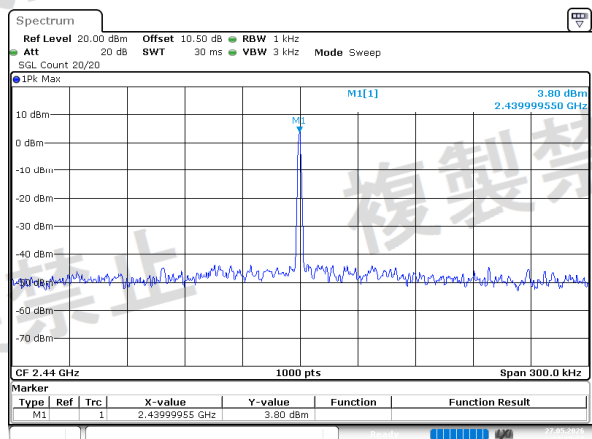
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:08:34

2402MHz



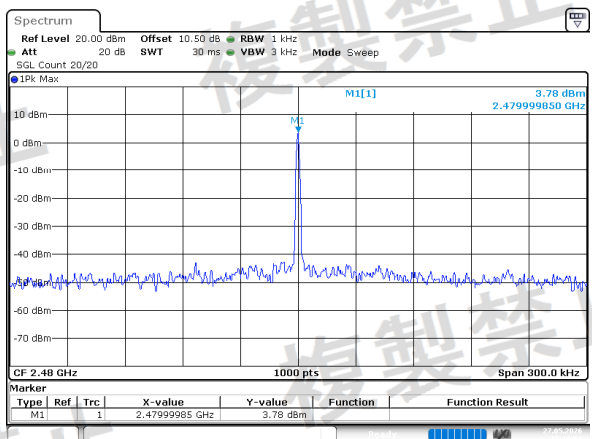
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:19:00

2440MHz



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:19:27

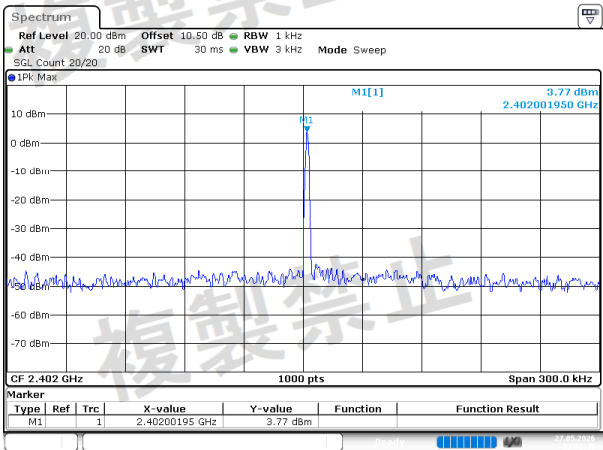
2480MHz



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:19:51

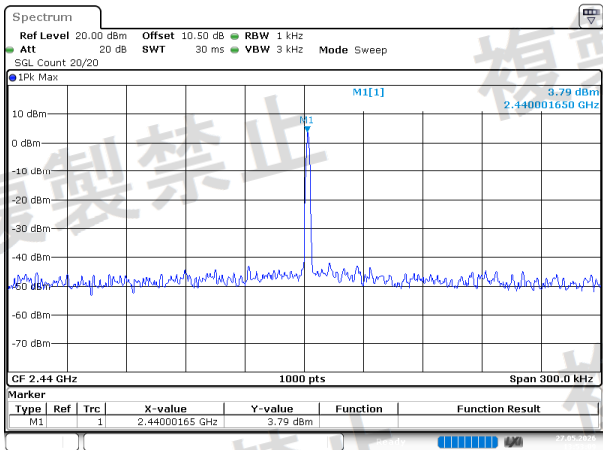
Test Condition: HV

2402MHz



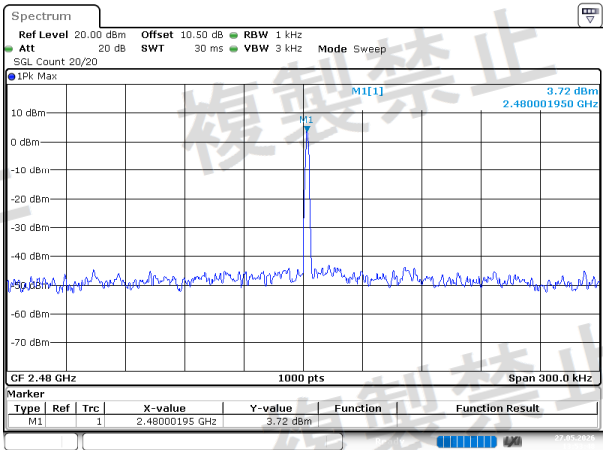
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:52:48

2440MHz



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:53:09

2480MHz



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:53:48

6.2 Occupied Bandwidth

Test Information:

Serial No.:	3KEN-1	Test Date:	2026/05/27
Test Site:	RF	Test Mode:	Transmitting
Tester:	Harper Shen	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	27.2	Relative Humidity: (%)	59	ATM Pressure: (kPa)	100.2
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Test Equipment List and Details:

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date	Calibration Agency	Calibration Method
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R&S	Coaxial Attenuator	10dB	F-08-EM512	2026/03/30	2027/03/29	BACL(DG)	D
JD	Test Software	JD Auto Test System	V1.0	N/A	N/A	N/A	N/A
All-sun	Clamp Meter	EM305A	8348897	2025/8/18	2026/8/17	BACL Metrology	C
Emerson	DC Power Supply	ONU4820	210213035320950100A0	N/A	N/A	N/A	N/A

* Statement of Traceability: Bay Area Compliance Laboratories Corp. (Dongguan) attests that all calibrations have been performed, traceable to National Primary Standards and International System of Units (SI).

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- Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated calibration agency under Article 102-18 paragraph (1).
- Calibration conducted by using measuring instruments and other equipment which shall have been given any of calibration, etc. listed above from a) to c).

Test Condition: NV

Mode	Occupied bandwidth (MHz)			Limit(MHz)	Verdict
	Low Channel	Middle Channel	High Channel		
BLE 1M	1.045	1.06	1.06	≤ 26	Pass
BLE 2M	1.975	2.015	2.05		Pass

Test Condition: LV

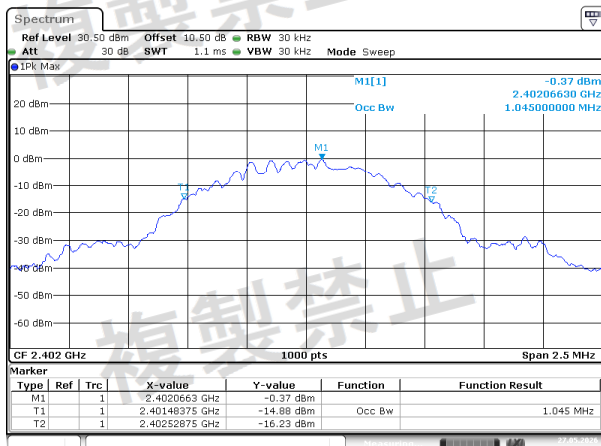
Mode	Occupied bandwidth (MHz)			Limit(MHz)	Verdict
	Low Channel	Middle Channel	High Channel		
BLE 1M	1.045	1.06	1.06	≤ 26	Pass
BLE 2M	1.97	2.02	2.05		Pass

Test Condition: HV

Mode	Occupied bandwidth (MHz)			Limit(MHz)	Verdict
	Low Channel	Middle Channel	High Channel		
BLE 1M	1.045	1.063	1.06	≤ 26	Pass
BLE 2M	1.975	2.02	2.05		Pass

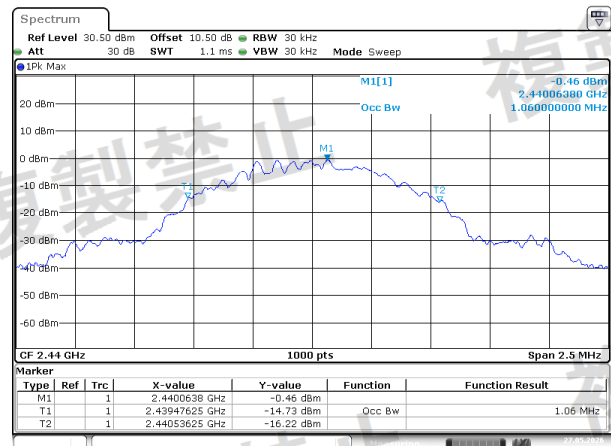
Test Condition: NV

BLE 1M_Low Channel



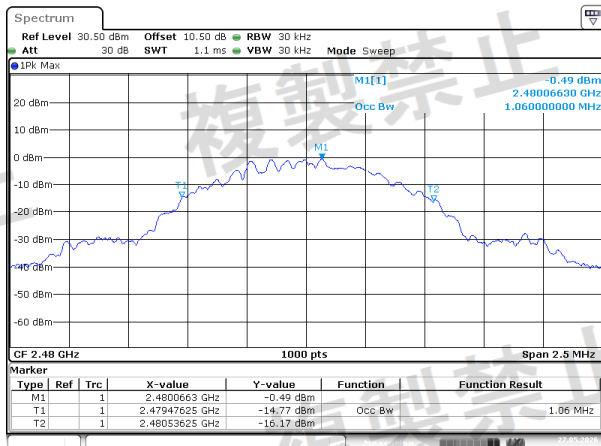
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:10:50

BLE 1M_Middle Channel



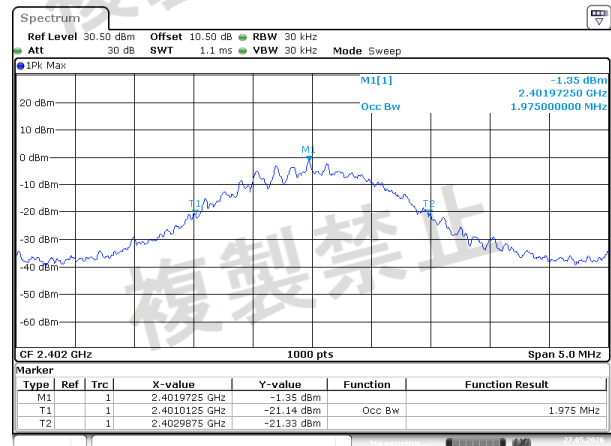
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:11:26

BLE 1M_High Channel



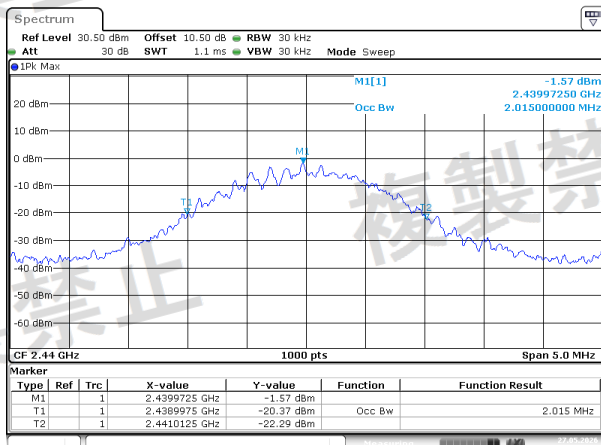
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:12:30

BLE 2M_Low Channel



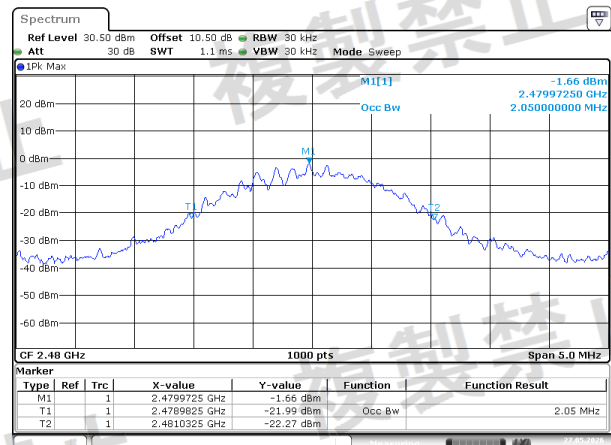
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:13:13

BLE 2M_Middle Channel



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:13:52

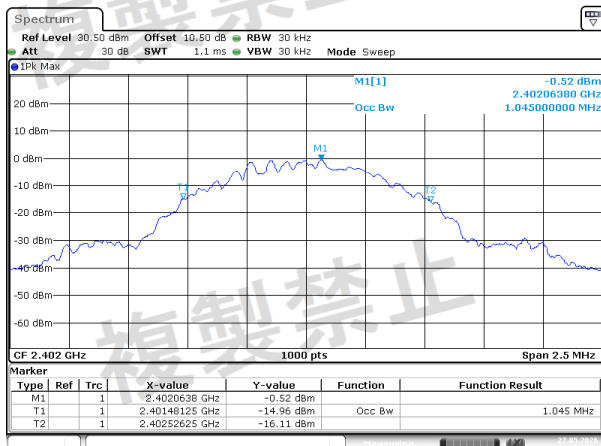
BLE 2M_High Channel



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:17:39

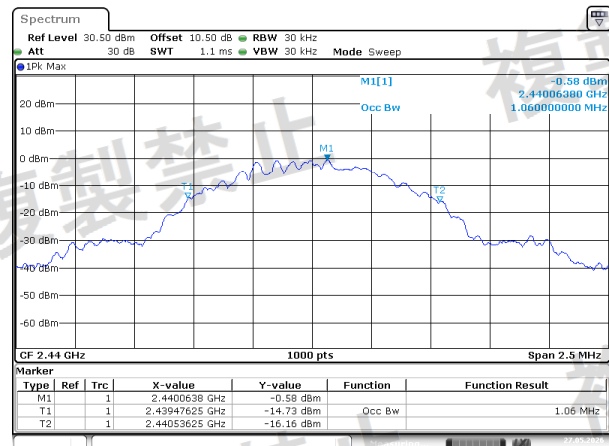
Test Condition: LV

BLE 1M_Low Channel



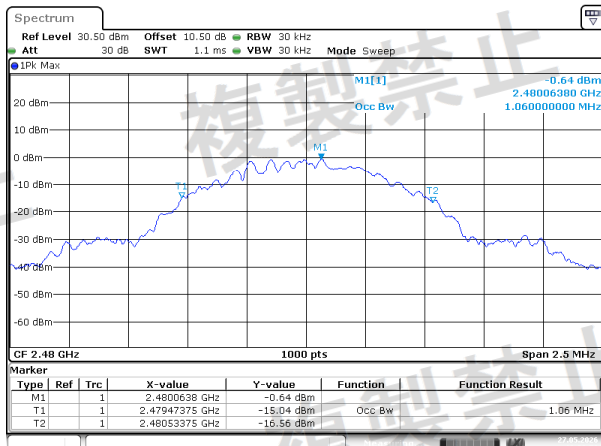
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:28:44

BLE 1M_Middle Channel



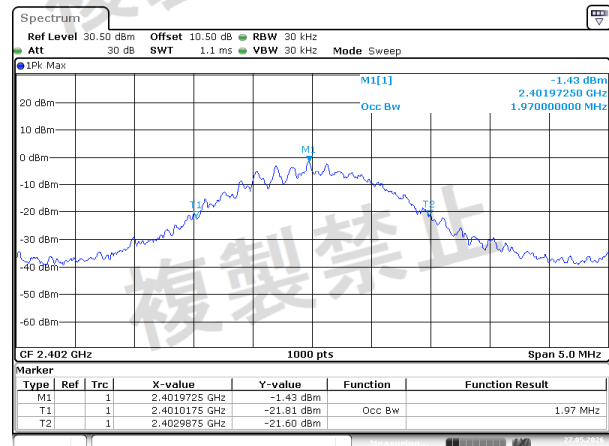
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:29:23

BLE 1M_High Channel



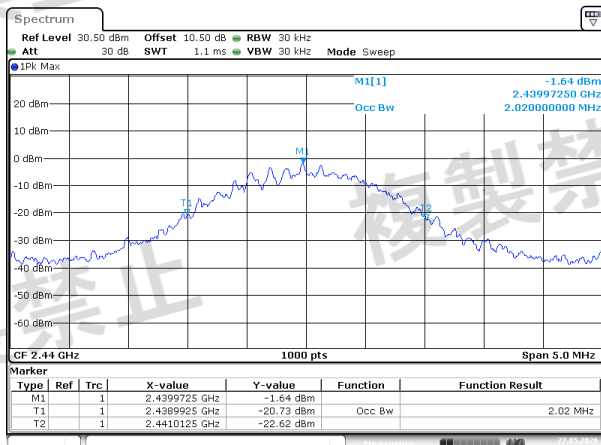
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Date: 27.MAY.2026 13:29:52

BLE 2M_Low Channel



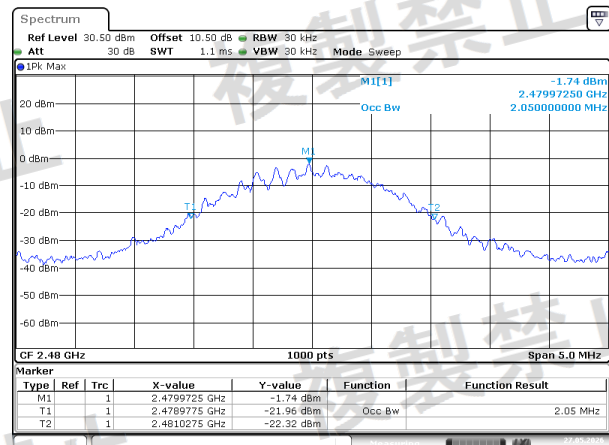
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Date: 27.MAY.2026 13:30:23

BLE 2M_Middle Channel



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:31:27

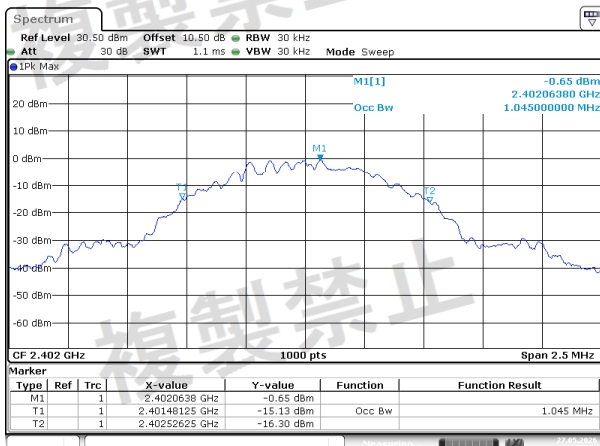
BLE 2M_High Channel



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:31:55

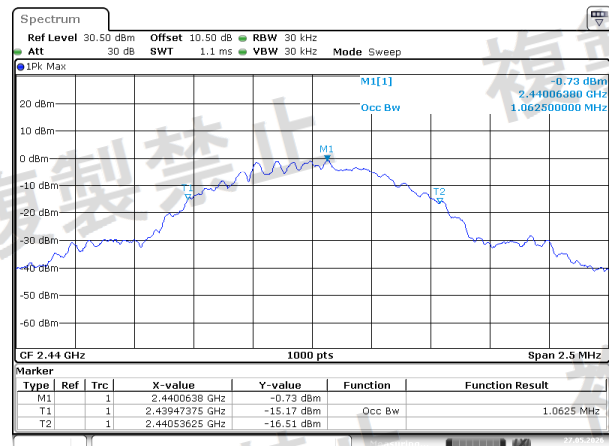
Test Condition: HV

BLE 1M_Low Channel



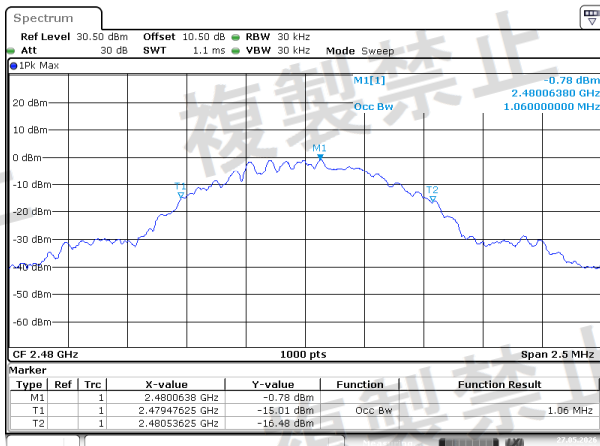
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:55:47

BLE 1M_Middle Channel



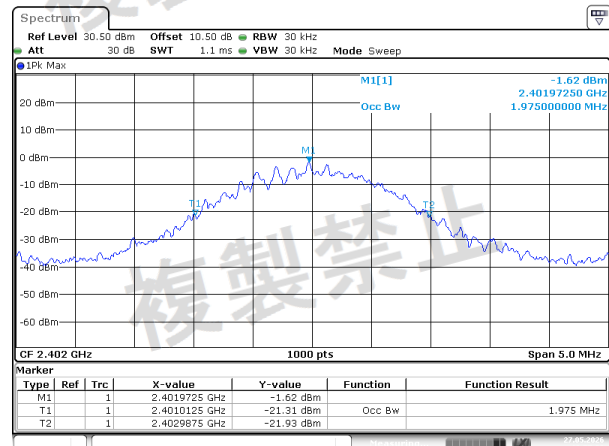
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:56:20

BLE 1M_High Channel



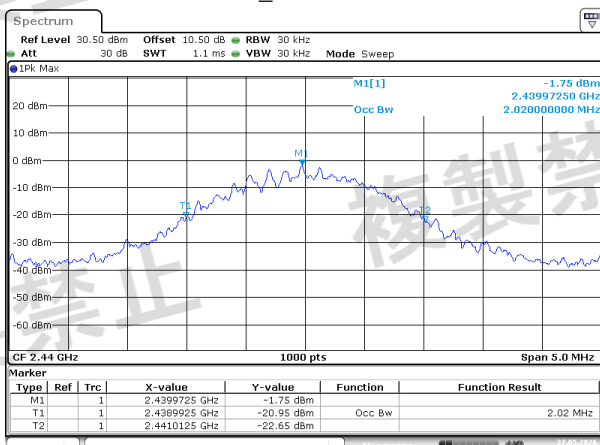
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:56:56

BLE 2M_Low Channel



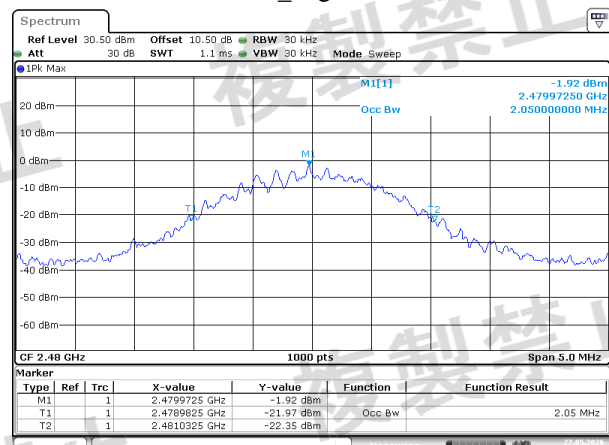
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:57:33

BLE 2M_Middle Channel



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:58:09

BLE 2M_High Channel



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:58:42

6.3 Transmitter Spurious Emission and Unwanted Emission Intensity

Test Information:

Serial No.:	3KEN-1	Test Date:	2026/05/27
Test Site:	RF	Test Mode:	Transmitting
Tester:	Harper Shen	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	27.2	Relative Humidity: (%)	59	ATM Pressure: (kPa)	100.2
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Test Equipment List and Details:

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date	Calibration Agency	Calibrati on Method
R&S	Spectrum Analyzer	FSV40	101589	2025/07/28	2026/07/27	BACL Metrology	C
HUBER+SUHNER	Coaxial Attenuator	6610_SMA-50-1	0064	2026/03/30	2027/03/29	BACL(DG)	D
R&S	Coaxial Attenuator	10dB	F-08-EM512	2026/03/30	2027/03/29	BACL(DG)	D
JD	Test Software	JD Auto Test System	V1.0	N/A	N/A	N/A	N/A
All-sun	Clamp Meter	EM305A	8348897	2025/8/18	2026/8/17	BACL Metrology	C
Emerson	DC Power Supply	ONU4820	210213035320 950100A0	N/A	N/A	N/A	N/A

* Statement of Traceability: Bay Area Compliance Laboratories Corp. (Dongguan) attests that all calibrations have been performed, traceable to National Primary Standards and International System of Units (SI).

Note:

- Calibration conducted by the National Institute of Information and Communications Technology (NICT) (hereinafter referred to as "NICT") or a designated calibration agency under Article 102-18 paragraph (1).
- Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Law (Law No. 51 of 1992).
- Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated calibration agency under Article 102-18 paragraph (1).
- Calibration conducted by using measuring instruments and other equipment which shall have been given any of calibration, etc. listed above from a) to c).

Test Condition: Normal, BLE 1M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	930.4	-66.79	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2378.33	-46.56	0.022	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9903	-27.39	1.824	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2486.4868	-56.41	0.002	25	Pass
	Band V (1MHz)	2496.5	12500	7205.6	-32.82	0.522	2.50	Pass
Middle	Band I (100kHz)	30	1000	909.55	-67.05	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2344.35	-53.31	0.005	2.50	Pass
	Band III (1MHz)	2387	2400	2392.0733	-54.01	0.004	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2488.3198	-55.84	0.003	25	Pass
	Band V (1MHz)	2496.5	12500	7320.7	-33.94	0.404	2.50	Pass
High	Band I (100kHz)	30	1000	924.1	-67.19	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2384.57	-52.99	0.005	2.50	Pass
	Band III (1MHz)	2387	2400	2395.2518	-57.18	0.002	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.6138	-33.12	0.488	25	Pass
	Band V (1MHz)	2496.5	12500	7440.7	-34.91	0.323	2.50	Pass

Test Condition: Normal, BLE 2M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	328.03	-65.98	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2379.02	-46.59	0.022	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9968	-16.95	20.184	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2489.6588	-56.48	0.002	25	Pass
	Band V (1MHz)	2496.5	12500	7205.6	-33.08	0.492	2.50	Pass
Middle	Band I (100kHz)	30	1000	956.11	-66.93	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2344.35	-52.90	0.005	2.50	Pass
	Band III (1MHz)	2387	2400	2392.0993	-53.85	0.004	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2488.8333	-56.00	0.003	25	Pass
	Band V (1MHz)	2496.5	12500	7320.7	-34.03	0.395	2.50	Pass
High	Band I (100kHz)	30	1000	717.49	-67.08	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2384.57	-52.32	0.006	2.50	Pass
	Band III (1MHz)	2387	2400	2395.1218	-56.89	0.002	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.5813	-25.20	3.020	25	Pass
	Band V (1MHz)	2496.5	12500	7440.7	-34.97	0.318	2.50	Pass

Test Condition: LV, BLE 1M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	846.98	-66.52	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2378.33	-46.56	0.022	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9968	-26.24	2.377	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2485.9603	-56.95	0.002	25	Pass
	Band V (1MHz)	2496.5	12500	7205.6	-32.49	0.564	2.50	Pass
Middle	Band I (100kHz)	30	1000	861.05	-66.73	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2344.35	-53.42	0.005	2.50	Pass
	Band III (1MHz)	2387	2400	2391.9238	-54.17	0.004	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2485.9213	-56.35	0.002	25	Pass
	Band V (1MHz)	2496.5	12500	7320.7	-33.43	0.454	2.50	Pass
High	Band I (100kHz)	30	1000	797.51	-66.56	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2383.88	-53.11	0.005	2.50	Pass
	Band III (1MHz)	2387	2400	2392.8078	-56.99	0.002	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2485.4338	-33.25	0.473	25	Pass
	Band V (1MHz)	2496.5	12500	7440.7	-34.61	0.346	2.50	Pass

Test Condition: LV, BLE 2M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	866.38	-66.81	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2378.33	-46.51	0.022	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9903	-16.69	21.429	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.6658	-56.49	0.002	25	Pass
	Band V (1MHz)	2496.5	12500	7205.6	-32.66	0.542	2.50	Pass
Middle	Band I (100kHz)	30	1000	892.57	-66.73	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2345.04	-53.23	0.005	2.50	Pass
	Band III (1MHz)	2387	2400	2391.6508	-54.36	0.004	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2488.0468	-56.37	0.002	25	Pass
	Band V (1MHz)	2496.5	12500	7320.7	-33.79	0.418	2.50	Pass
High	Band I (100kHz)	30	1000	905.18	-66.70	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2383.88	-52.73	0.005	2.50	Pass
	Band III (1MHz)	2387	2400	2391.8978	-56.92	0.002	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.6398	-25.00	3.162	25	Pass
	Band V (1MHz)	2496.5	12500	7440.7	-34.85	0.327	2.50	Pass

Test Condition: HV, BLE 1M

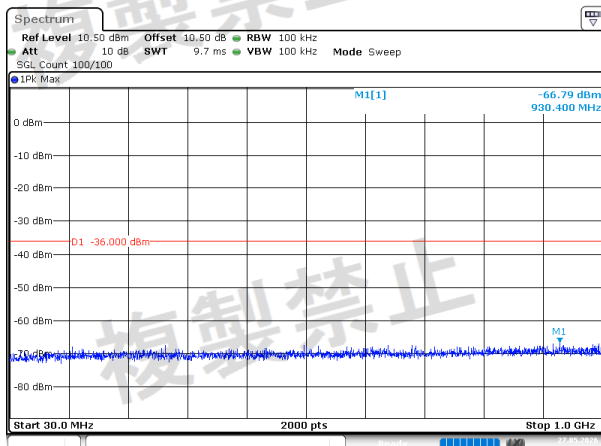
Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	870.26	-66.72	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2378.33	-46.77	0.021	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9903	-26.90	2.042	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2489.5288	-56.73	0.002	25	Pass
	Band V (1MHz)	2496.5	12500	7205.6	-32.03	0.627	2.50	Pass
Middle	Band I (100kHz)	30	1000	837.77	-65.70	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2345.04	-54.23	0.004	2.50	Pass
	Band III (1MHz)	2387	2400	2391.5208	-53.44	0.005	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2488.1183	-55.35	0.003	25	Pass
	Band V (1MHz)	2496.5	12500	7320.7	-33.17	0.482	2.50	Pass
High	Band I (100kHz)	30	1000	914.4	-65.97	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2383.88	-53.26	0.005	2.50	Pass
	Band III (1MHz)	2387	2400	2394.2703	-57.54	0.002	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2484.2378	-33.27	0.471	25	Pass
	Band V (1MHz)	2496.5	12500	7440.7	-34.85	0.327	2.50	Pass

Test Condition: HV, BLE 2M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	261.1	-66.95	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2378.33	-46.72	0.021	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9968	-17.34	18.450	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2495.3333	-56.35	0.002	25	Pass
	Band V (1MHz)	2496.5	12500	7205.6	-31.98	0.634	2.50	Pass
Middle	Band I (100kHz)	30	1000	951.26	-66.43	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2343.66	-53.59	0.004	2.50	Pass
	Band III (1MHz)	2387	2400	2391.5208	-53.80	0.004	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2487.9038	-55.26	0.003	25	Pass
	Band V (1MHz)	2496.5	12500	7320.7	-33.24	0.474	2.50	Pass
High	Band I (100kHz)	30	1000	931.37	-66.69	0.000	0.25	Pass
	Band II (1MHz)	1000	2387	2384.57	-52.73	0.005	2.50	Pass
	Band III (1MHz)	2387	2400	2399.5613	-56.80	0.002	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.5943	-25.44	2.858	25	Pass
	Band V (1MHz)	2496.5	12500	7440.7	-34.95	0.320	2.50	Pass

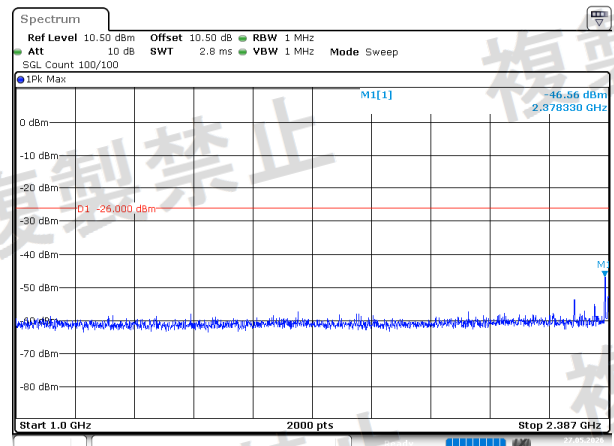
Test Condition: NV

BLE 1M_Low Channel(30MHz~1GHz)



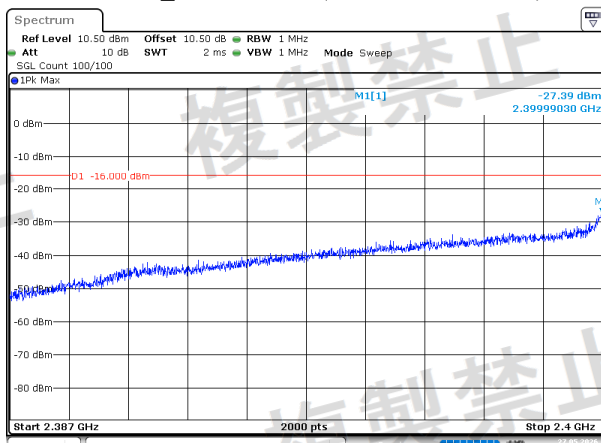
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:26:32

BLE 1M_Low Channel(1GHz~2.387GHz)



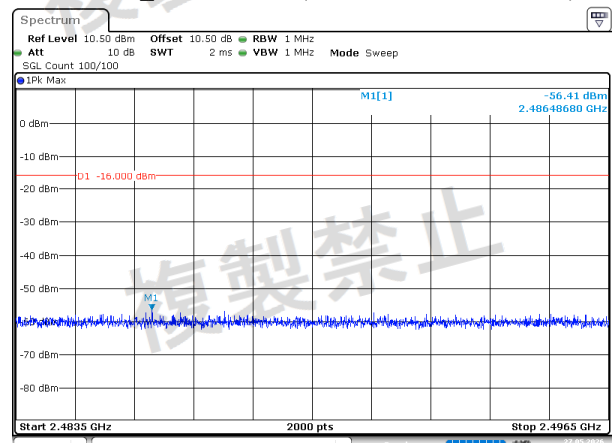
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:26:44

BLE 1M_Low Channel(2.387GHz~2.4GHz)



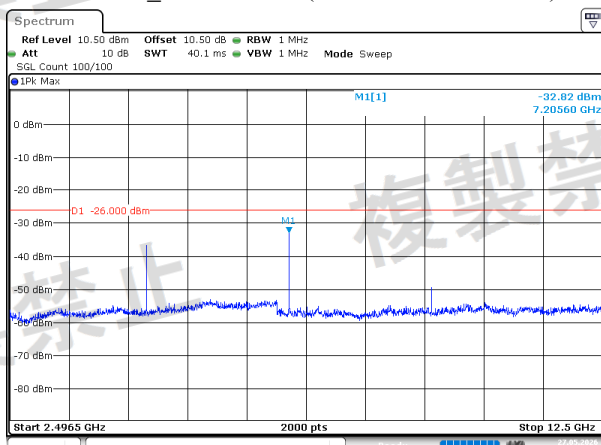
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:26:56

BLE 1M_Low Channel(2.4835GHz~2.4965GHz)



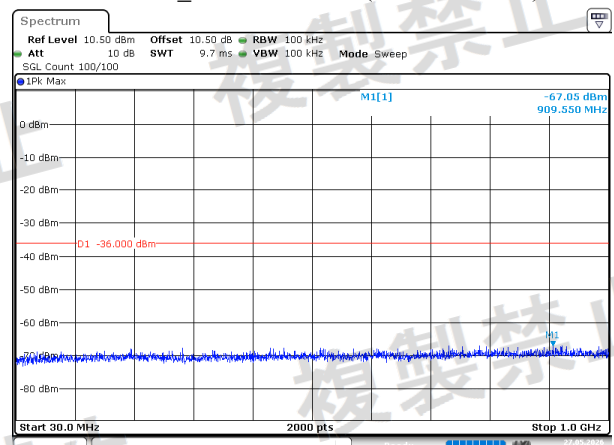
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:27:08

BLE 1M_Low Channel(2.4965GHz~12.5GHz)



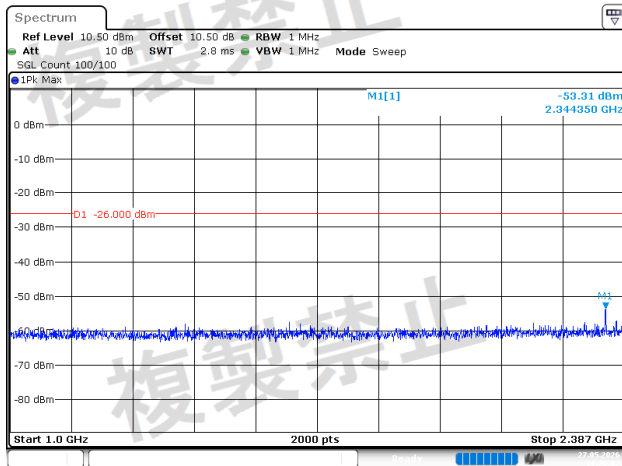
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:27:33

BLE 1M_Middle Channel(30MHz~1GHz)



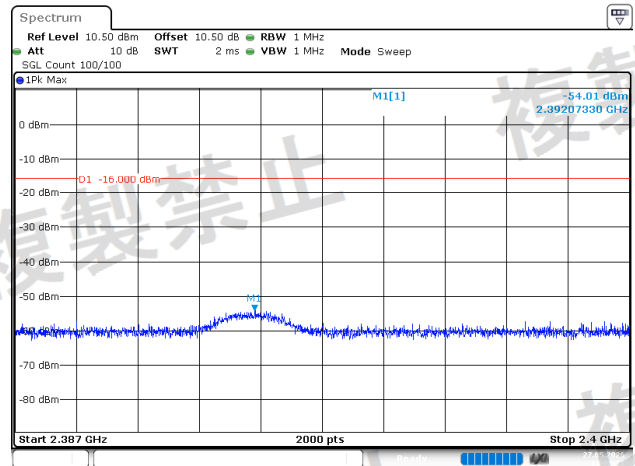
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:27:57

BLE 1M_Middle Channel(1GHz~2.387GHz)



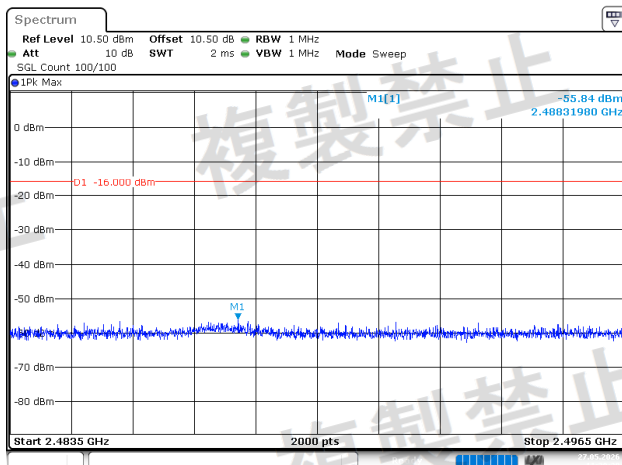
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:28:08

BLE 1M_Middle Channel(2.387GHz~2.4GHz)



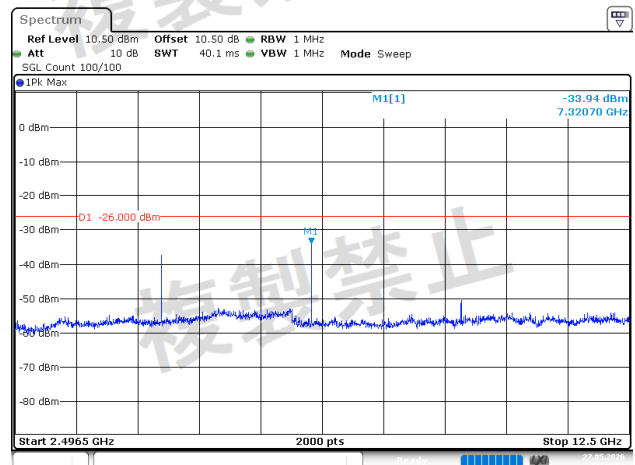
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:28:18

BLE 1M_Middle Channel(2.4835GHz~2.4965GHz)



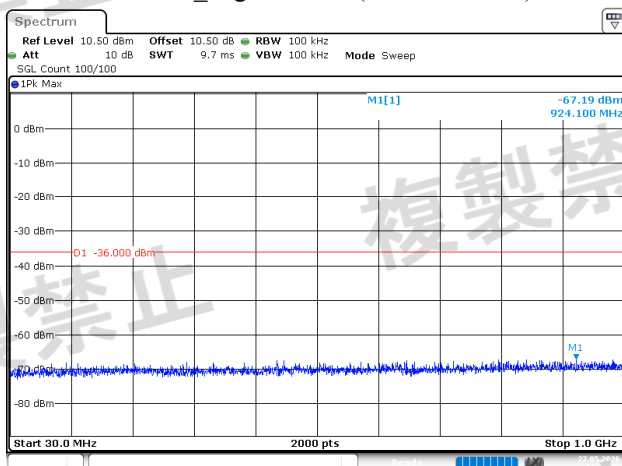
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:28:29

BLE 1M_Middle Channel(2.4965GHz~12.5GHz)



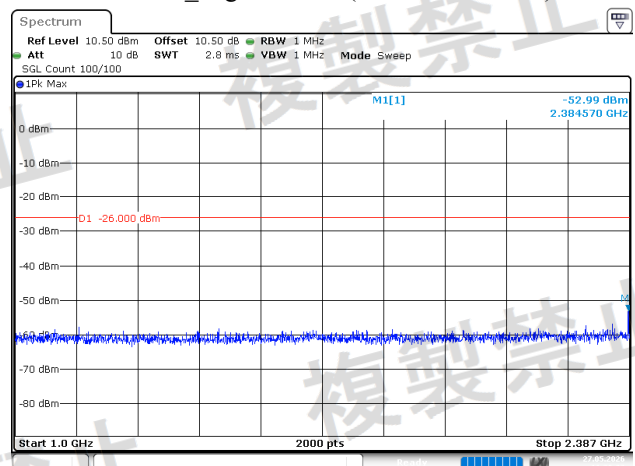
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:28:53

BLE 1M_High Channel(30MHz~1GHz)



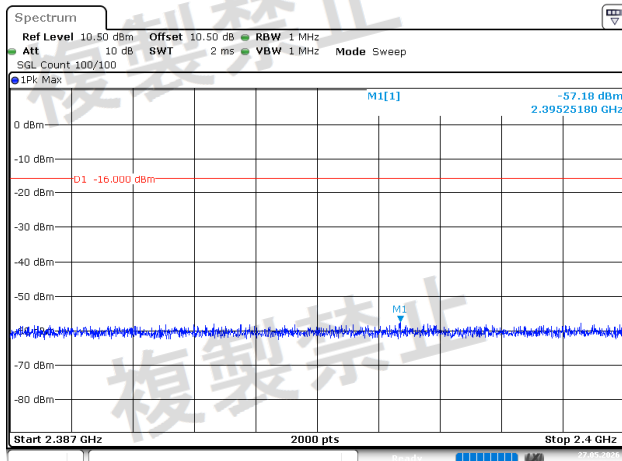
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:29:21

BLE 1M_High Channel(1GHz~2.387GHz)



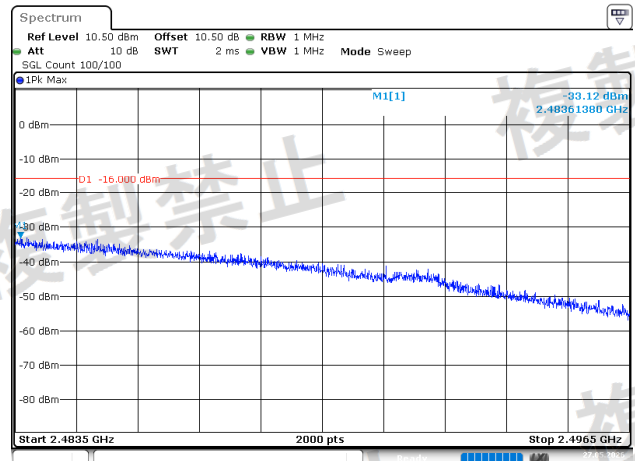
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:29:32

BLE 1M_High Channel(2.387GHz~2.4GHz)



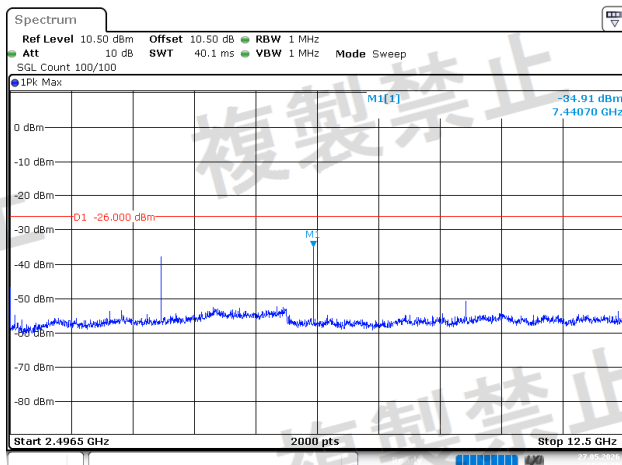
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:29:43

BLE 1M_High Channel(2.4835GHz~2.4965GHz)



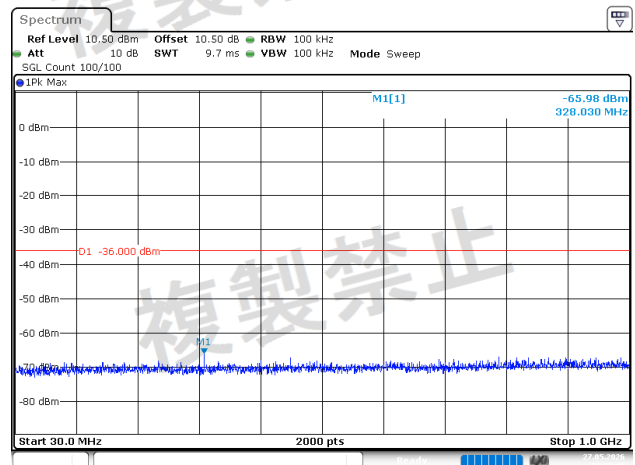
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:29:54

BLE 1M_High Channel(2.4965GHz~12.5GHz)



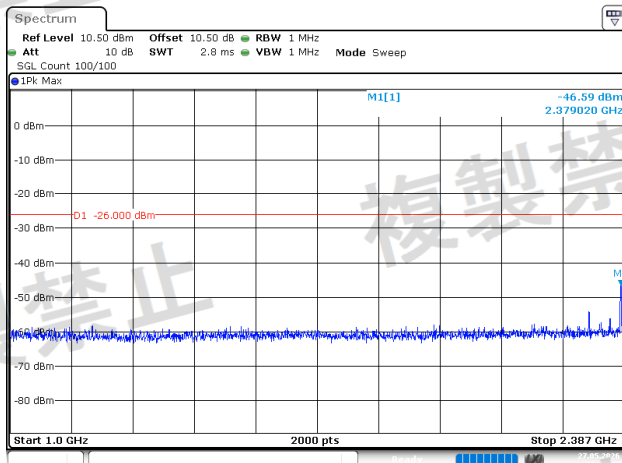
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:30:20

BLE 2M_Low Channel(30MHz~1GHz)



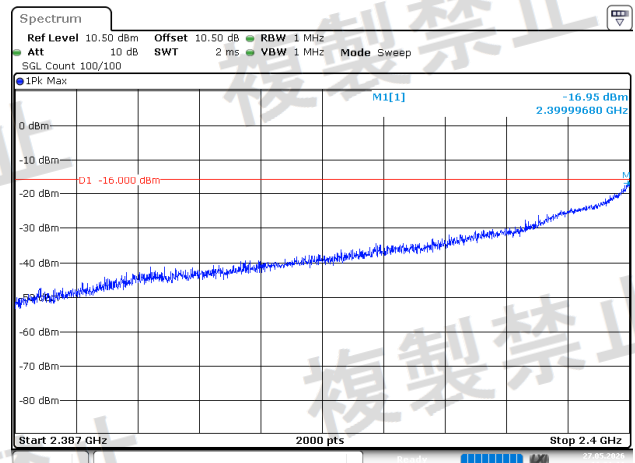
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:30:48

BLE 2M_Low Channel(1GHz~2.387GHz)



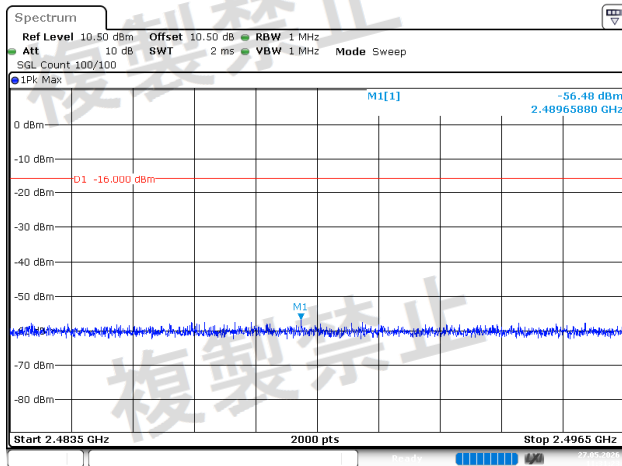
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:31:00

BLE 2M_Low Channel(2.387GHz~2.4GHz)

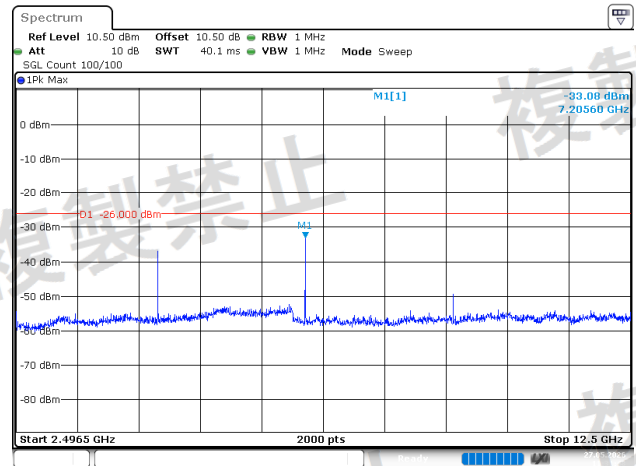


ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:31:11

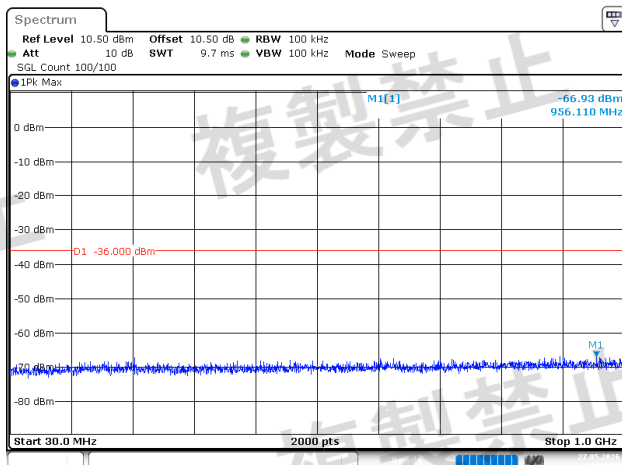
BLE 2M_Low Channel(2.4835GHz~2.4965GHz)



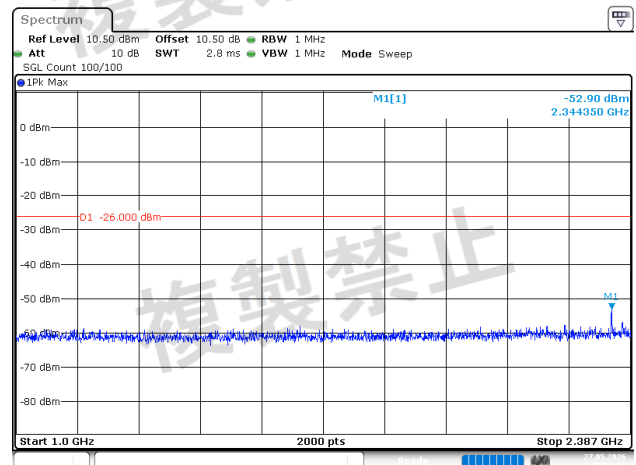
BLE 2M_Low Channel(2.4965GHz~12.5GHz)



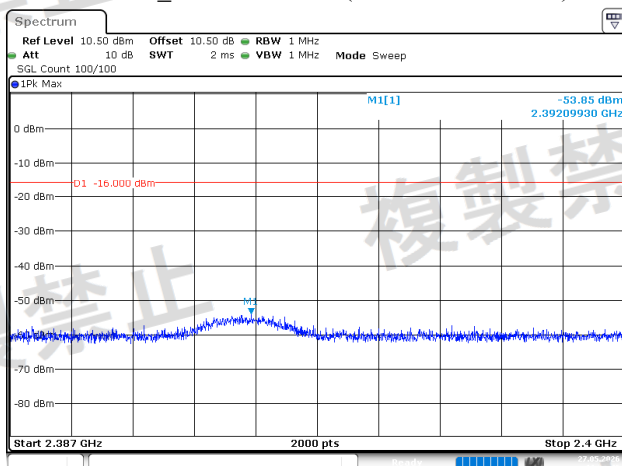
BLE 2M_Middle Channel(30MHz~1GHz)



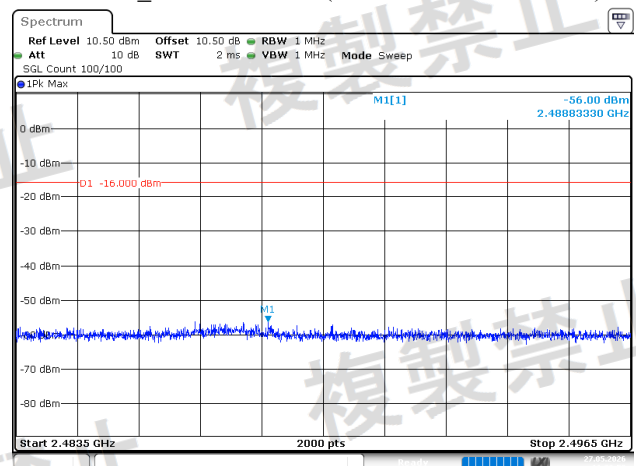
BLE 2M_Middle Channel(1GHz~2.387GHz)



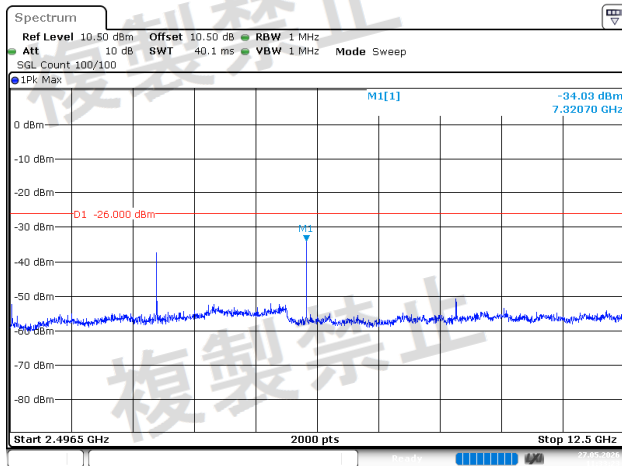
BLE 2M_Middle Channel(2.387GHz~2.4GHz)



BLE 2M_Middle Channel(2.4835GHz~2.4965GHz)

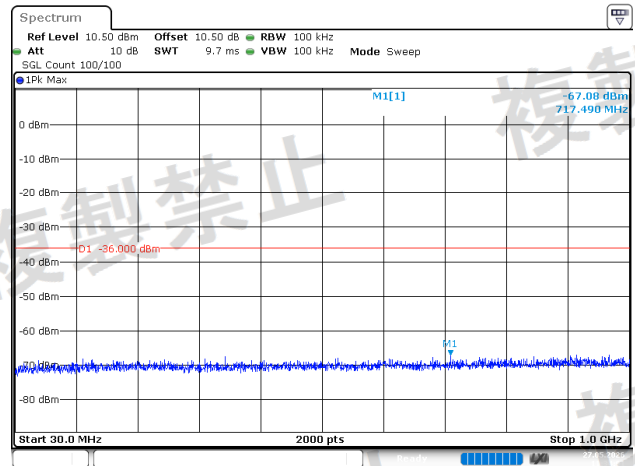


BLE 2M_Middle Channel(2.4965GHz~12.5GHz)



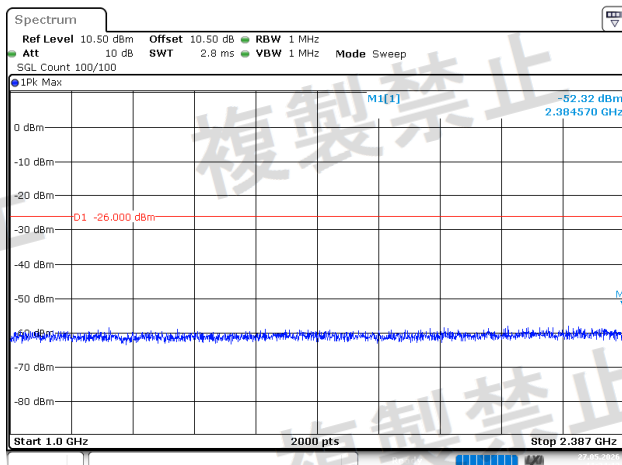
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:33:23

BLE 2M_High Channel(30MHz~1GHz)



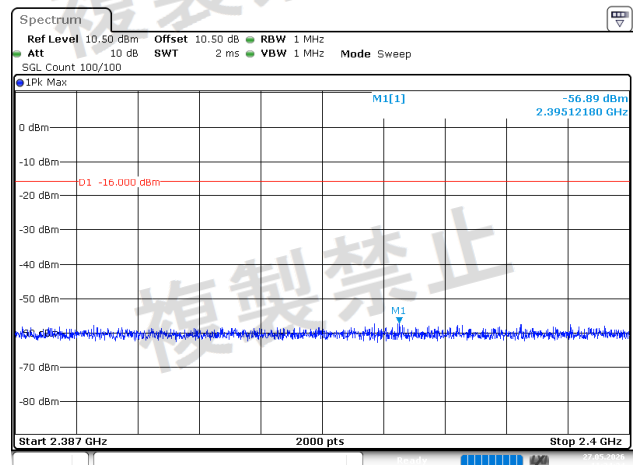
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:34:01

BLE 2M_High Channel(1GHz~2.387GHz)



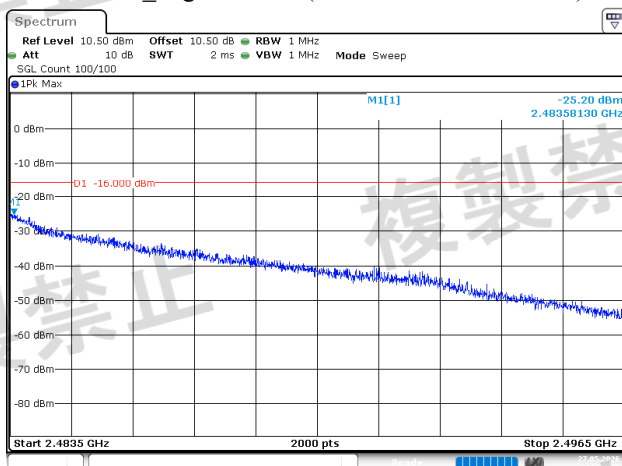
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:34:12

BLE 2M_High Channel(2.387GHz~2.4GHz)



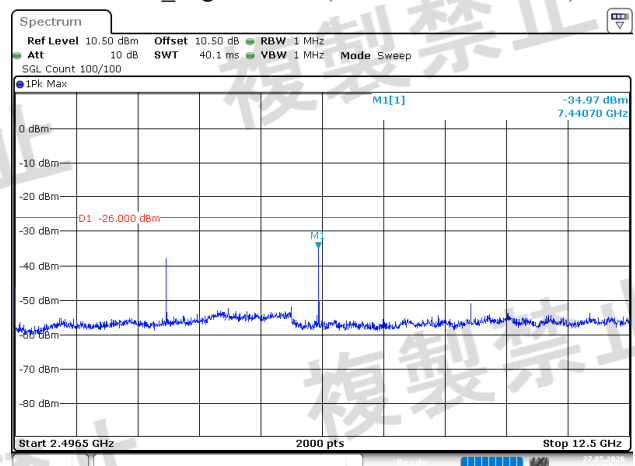
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:34:24

BLE 2M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:34:35

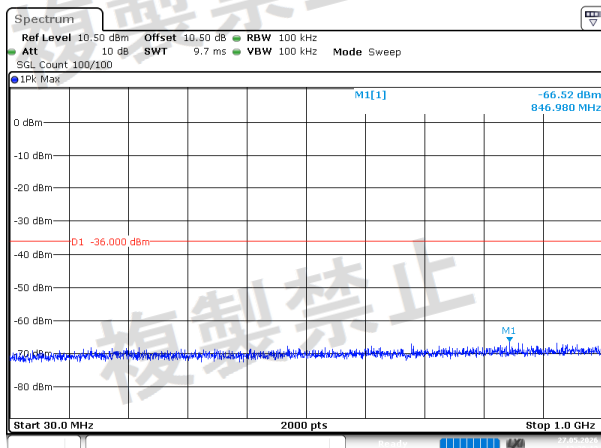
BLE 2M_High Channel(2.4965GHz~12.5GHz)



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:34:59

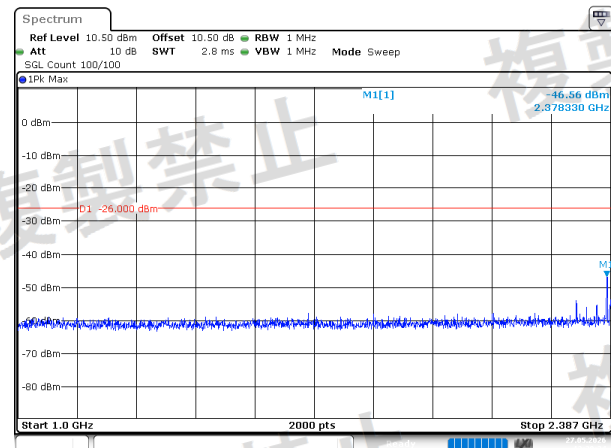
Test Condition: LV

BLE 1M_Low Channel(30MHz~1GHz)



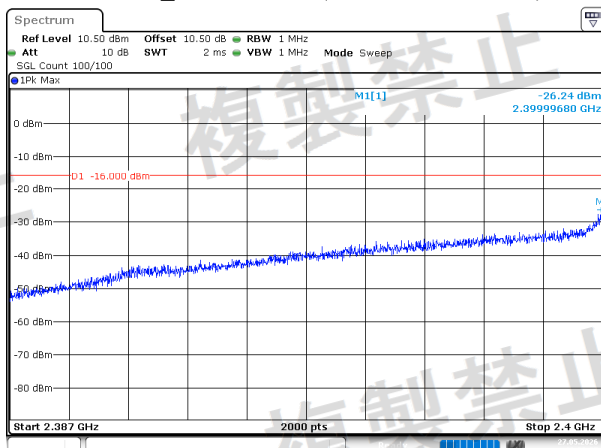
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:38:13

BLE 1M_Low Channel(1GHz~2.387GHz)



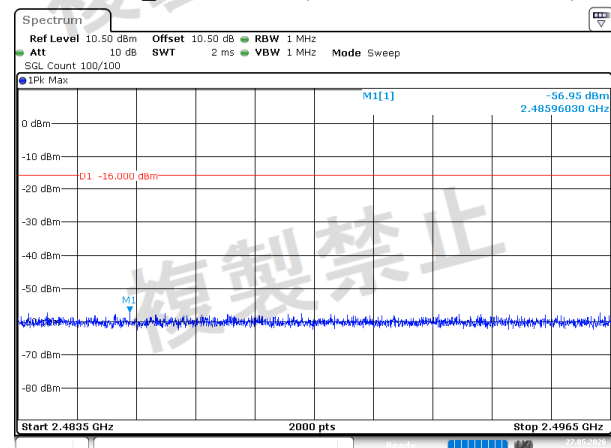
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:38:24

BLE 1M_Low Channel(2.387GHz~2.4GHz)



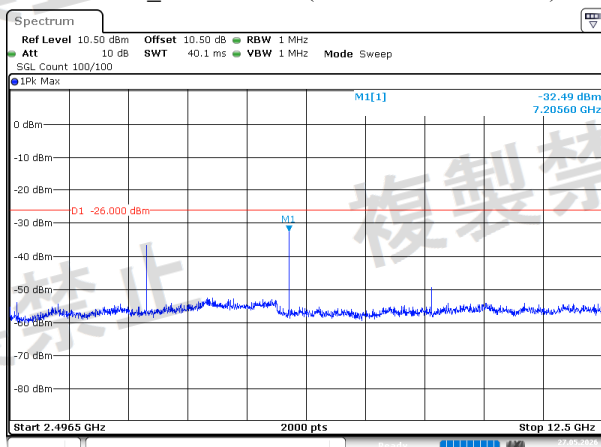
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:38:35

BLE 1M_Low Channel(2.4835GHz~2.4965GHz)



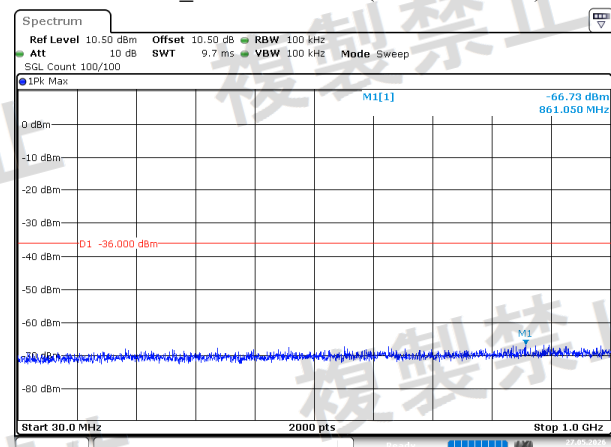
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:38:46

BLE 1M_Low Channel(2.4965GHz~12.5GHz)



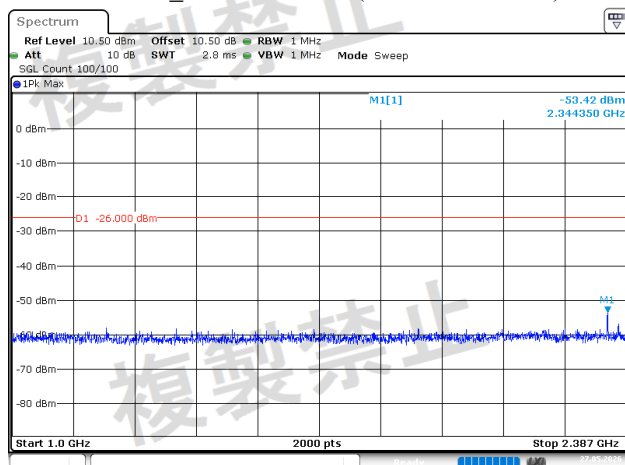
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:39:11

BLE 1M_Middle Channel(30MHz~1GHz)



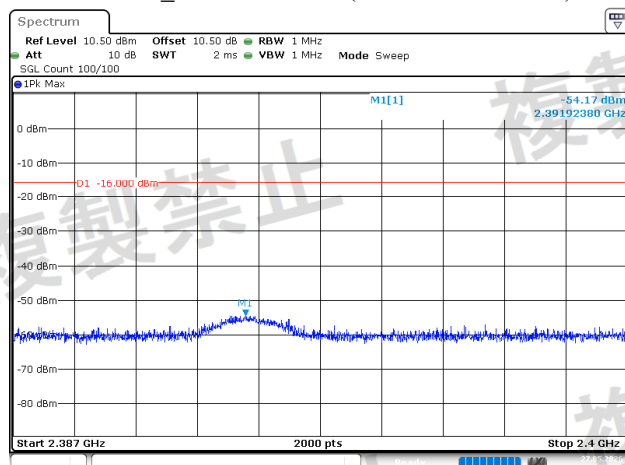
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:39:39

BLE 1M_Middle Channel(1GHz~2.387GHz)



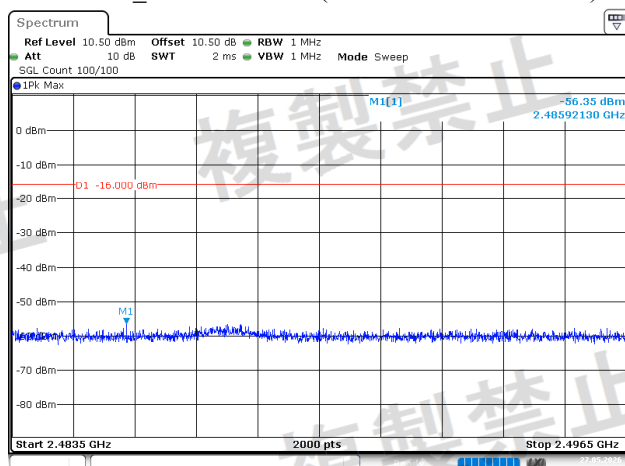
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:39:51

BLE 1M_Middle Channel(2.387GHz~2.4GHz)



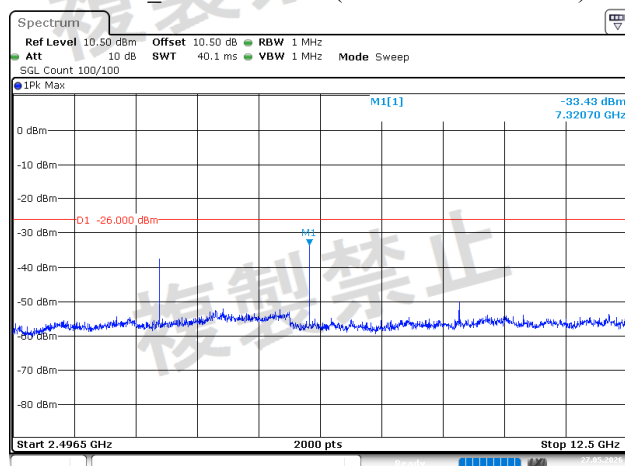
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:40:01

BLE 1M_Middle Channel(2.4835GHz~2.4965GHz)



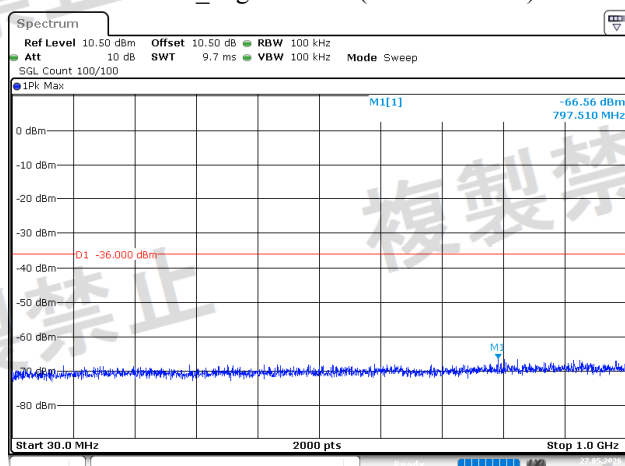
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:40:12

BLE 1M_Middle Channel(2.4965GHz~12.5GHz)



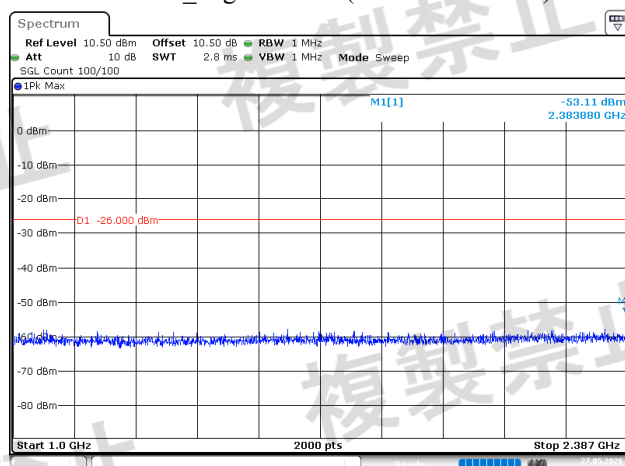
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:40:36

BLE 1M_High Channel(30MHz~1GHz)



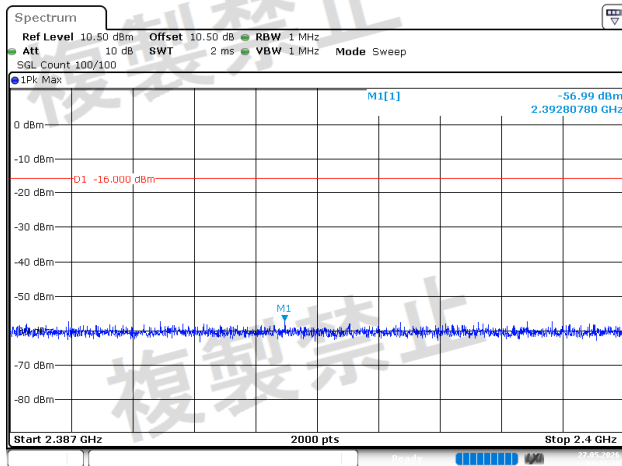
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:41:00

BLE 1M_High Channel(1GHz~2.387GHz)

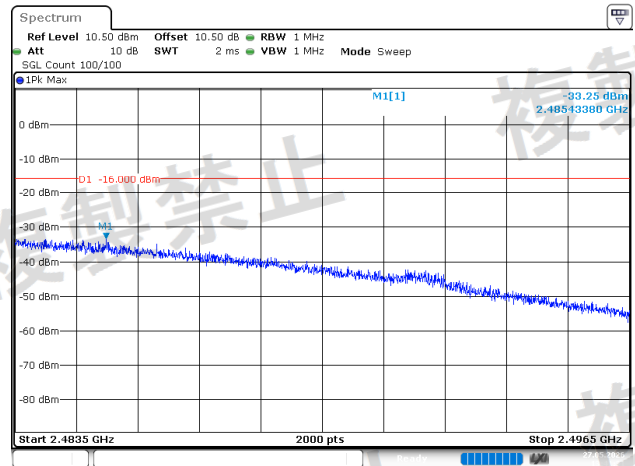


ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:41:11

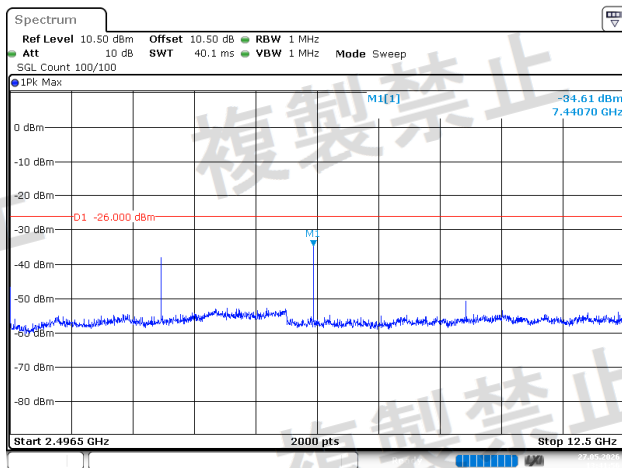
BLE 1M_High Channel(2.387GHz~2.4GHz)



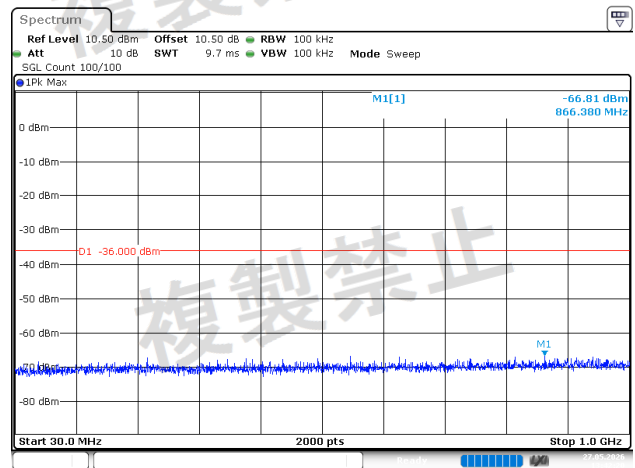
BLE 1M_High Channel(2.4835GHz~2.4965GHz)



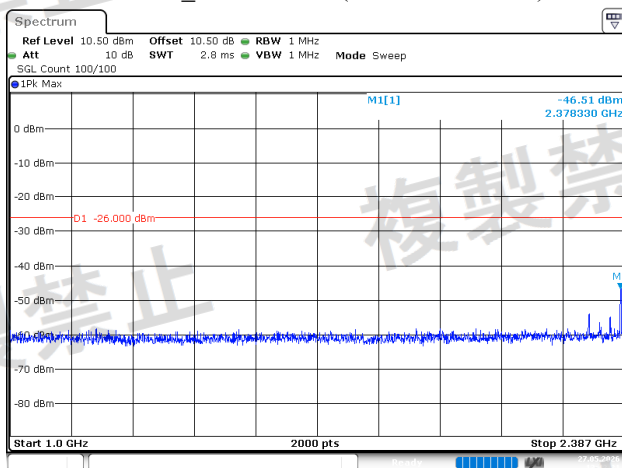
BLE 1M_High Channel(2.4965GHz~12.5GHz)



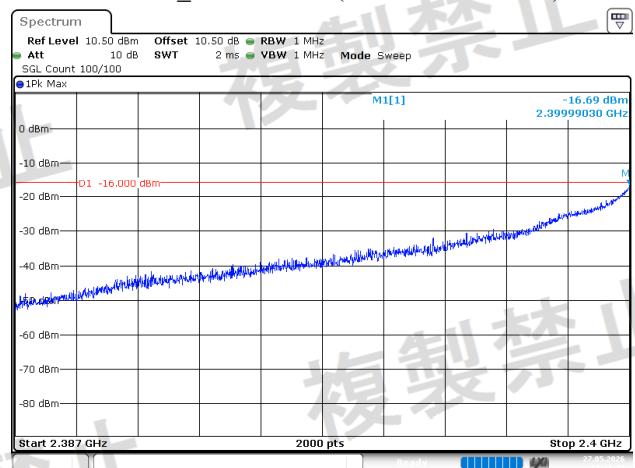
BLE 2M_Low Channel(30MHz~1GHz)



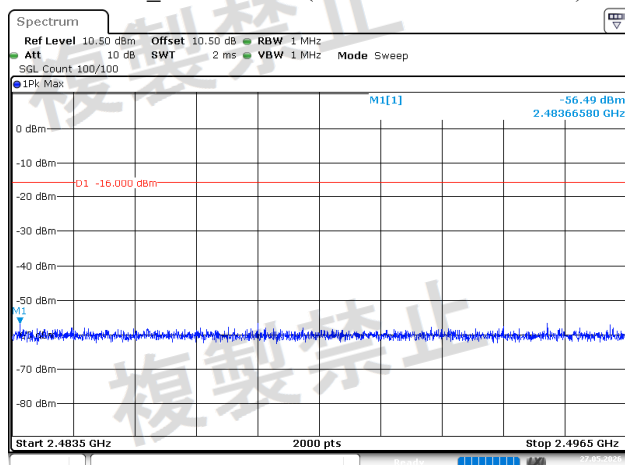
BLE 2M_Low Channel(1GHz~2.387GHz)



BLE 2M_Low Channel(2.387GHz~2.4GHz)

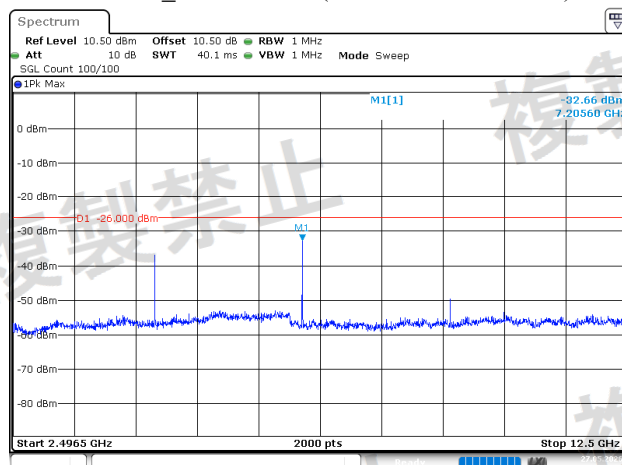


BLE 2M_Low Channel(2.4835GHz~2.4965GHz)



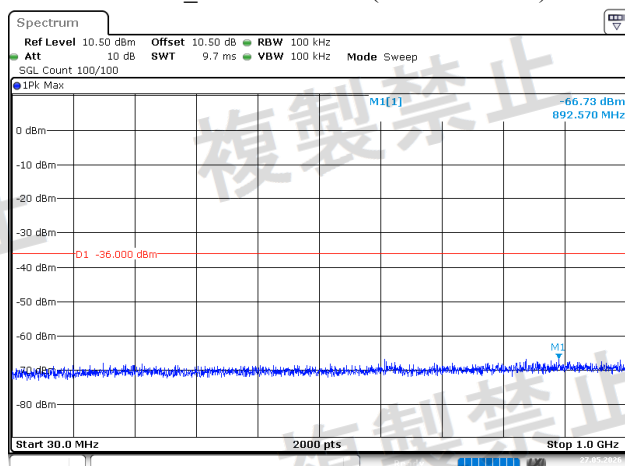
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:42:53

BLE 2M_Low Channel(2.4965GHz~12.5GHz)



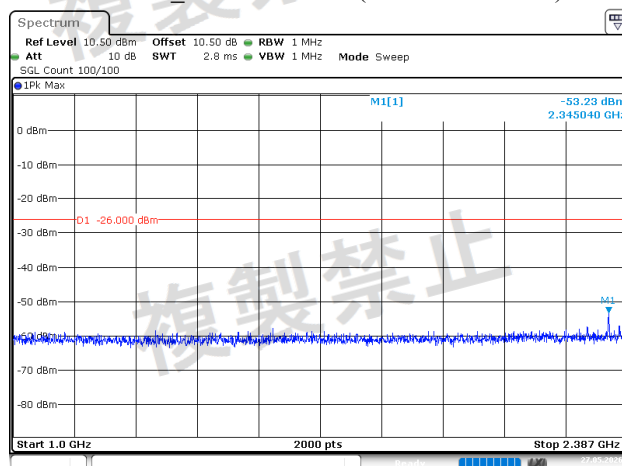
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:43:16

BLE 2M_Middle Channel(30MHz~1GHz)



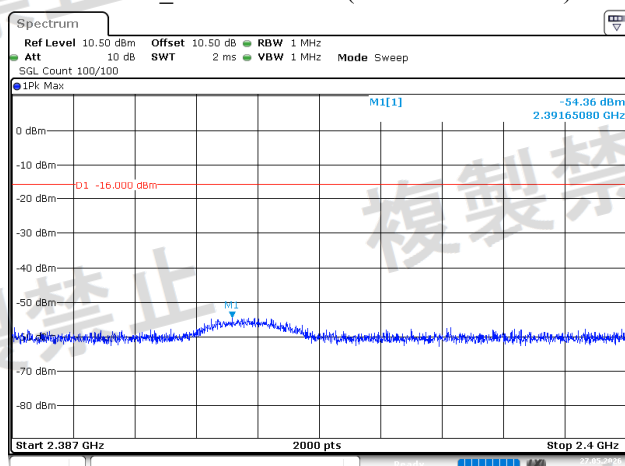
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:43:35

BLE 2M_Middle Channel(1GHz~2.387GHz)



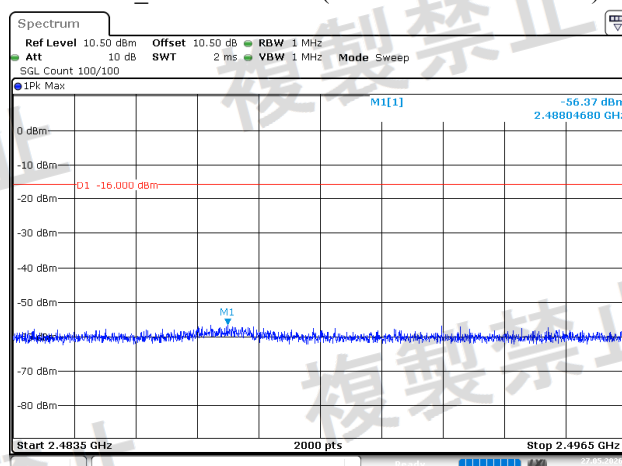
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:43:46

BLE 2M_Middle Channel(2.387GHz~2.4GHz)



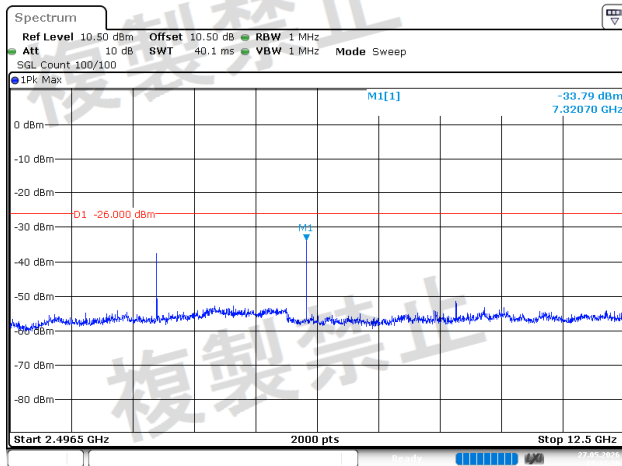
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:43:56

BLE 2M_Middle Channel(2.4835GHz~2.4965GHz)



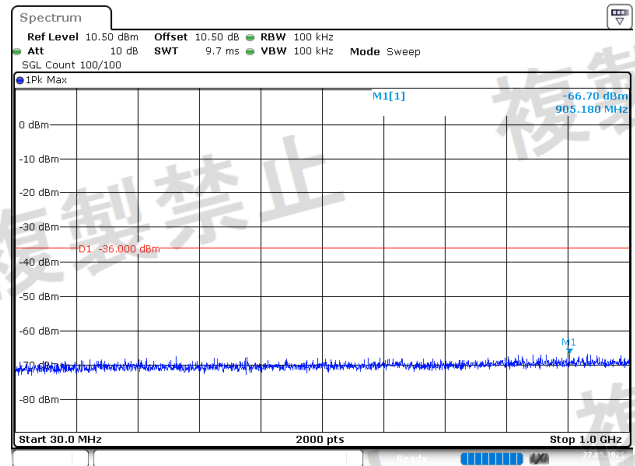
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:44:06

BLE 2M_Middle Channel(2.4965GHz~12.5GHz)



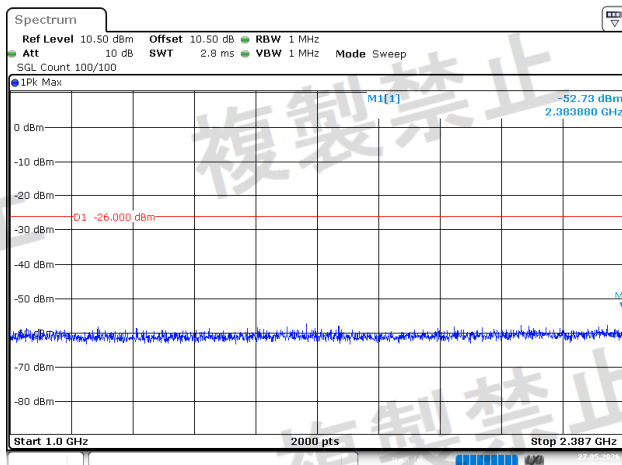
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:44:30

BLE 2M_High Channel(30MHz~1GHz)



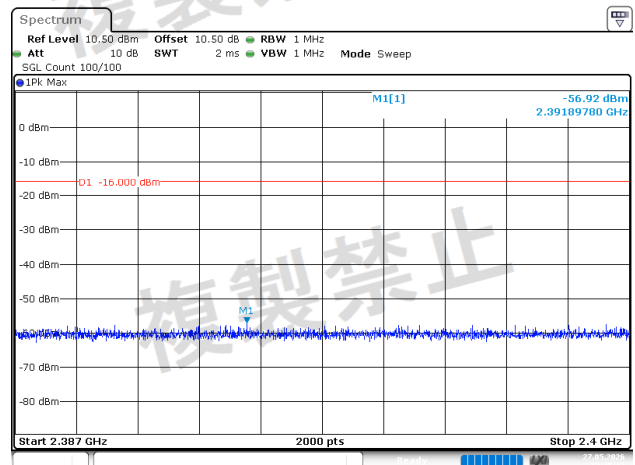
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:44:50

BLE 2M_High Channel(1GHz~2.387GHz)



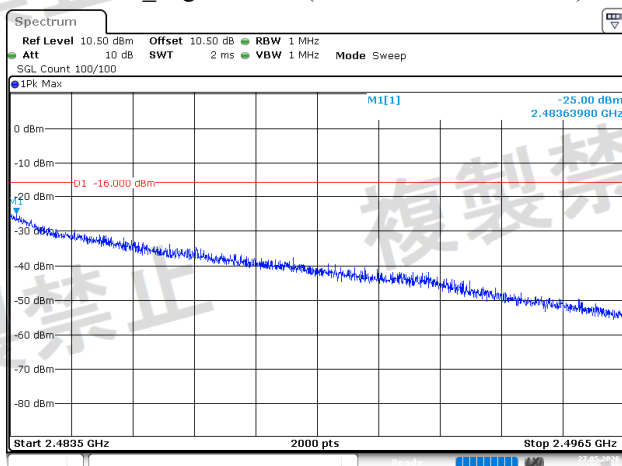
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:45:02

BLE 2M_High Channel(2.387GHz~2.4GHz)



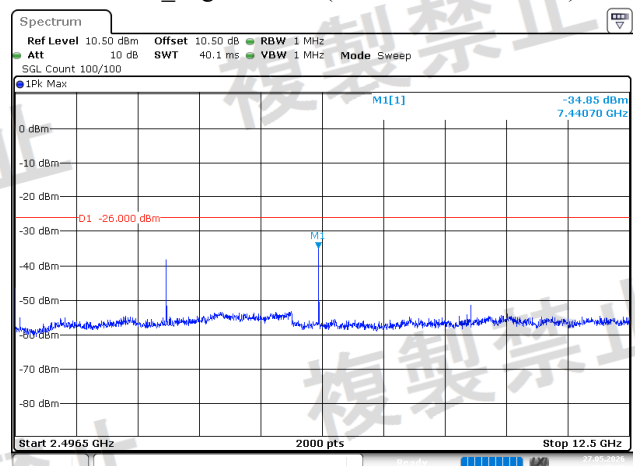
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:45:13

BLE 2M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:45:23

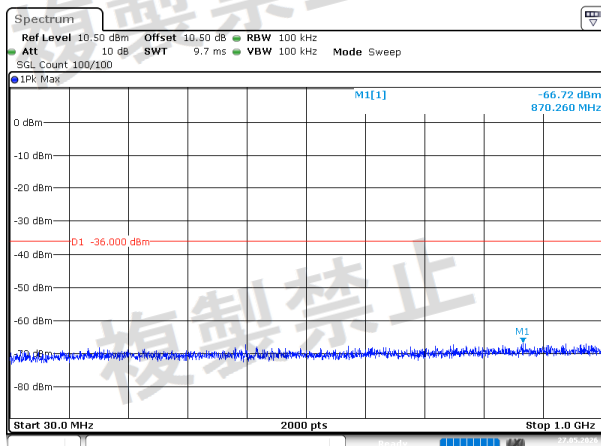
BLE 2M_High Channel(2.4965GHz~12.5GHz)



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:45:47

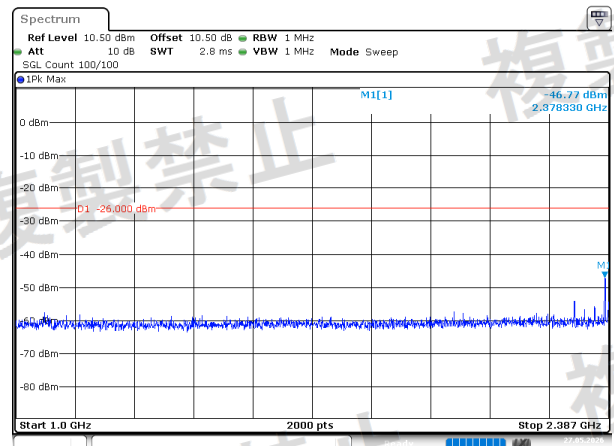
Test Condition: HV

BLE 1M_Low Channel(30MHz~1GHz)



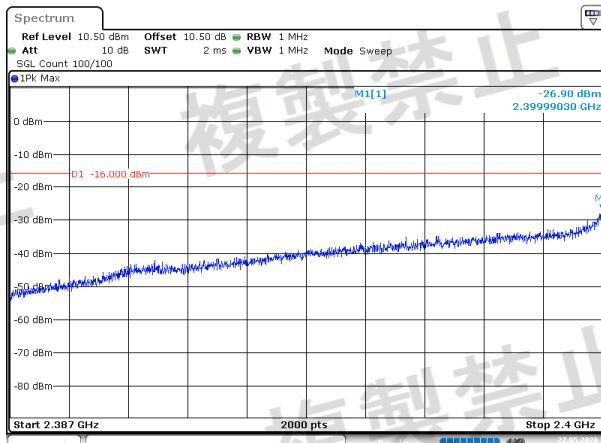
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 14:05:02

BLE 1M_Low Channel(1GHz~2.387GHz)



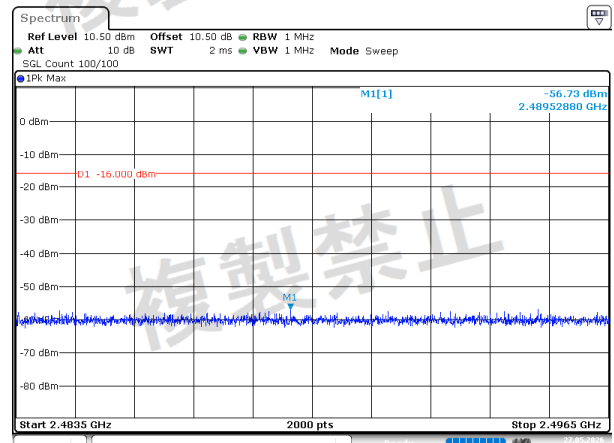
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 14:05:13

BLE 1M_Low Channel(2.387GHz~2.4GHz)



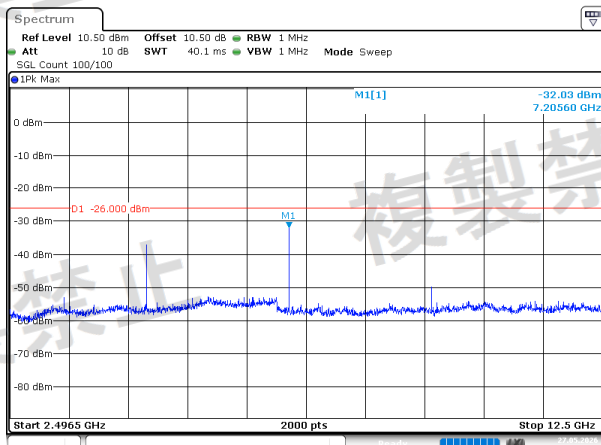
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 14:05:23

BLE 1M_Low Channel(2.4835GHz~2.4965GHz)



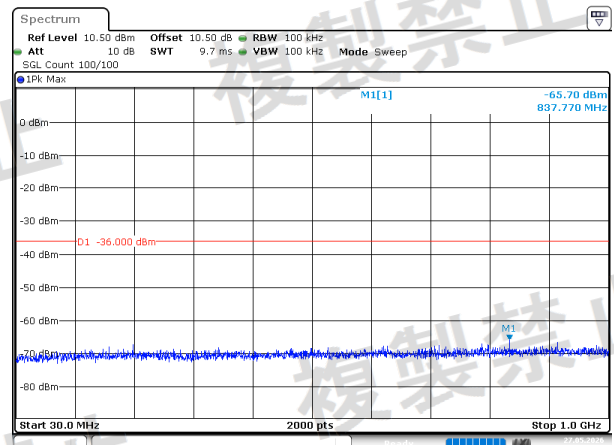
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 14:05:33

BLE 1M_Low Channel(2.4965GHz~12.5GHz)



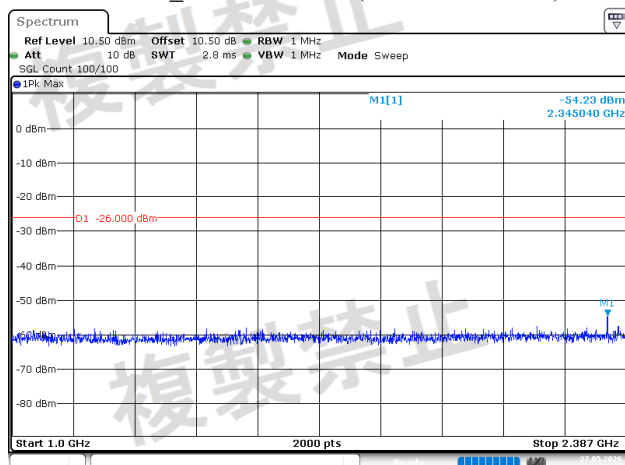
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 14:05:57

BLE 1M_Middle Channel(30MHz~1GHz)



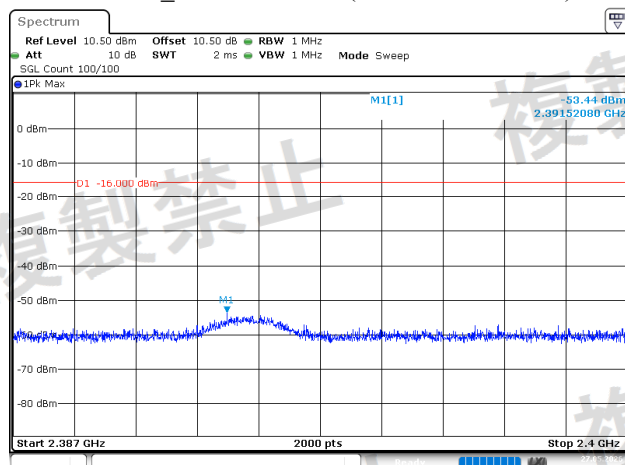
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 14:06:16

BLE 1M_Middle Channel(1GHz~2.387GHz)



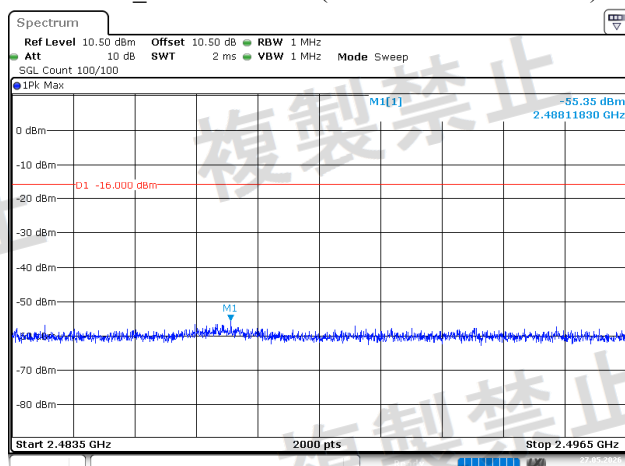
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 14:06:26

BLE 1M_Middle Channel(2.387GHz~2.4GHz)



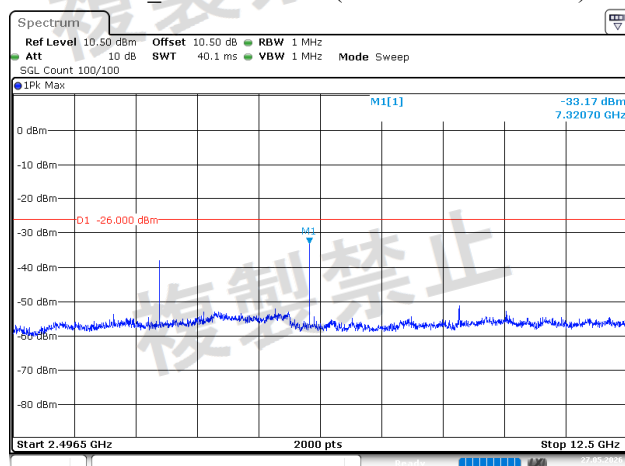
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 14:06:36

BLE 1M_Middle Channel(2.4835GHz~2.4965GHz)



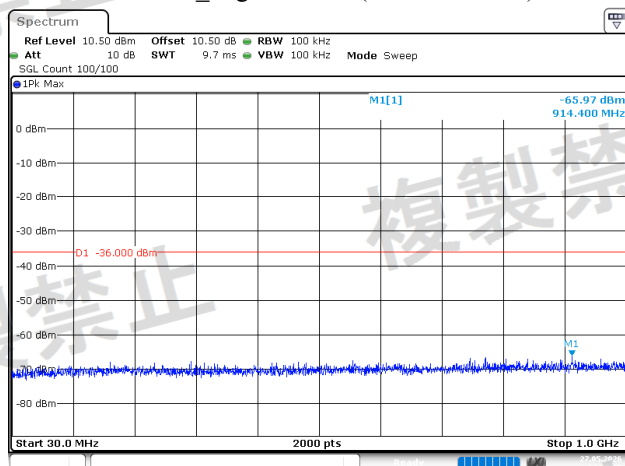
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 14:06:47

BLE 1M_Middle Channel(2.4965GHz~12.5GHz)



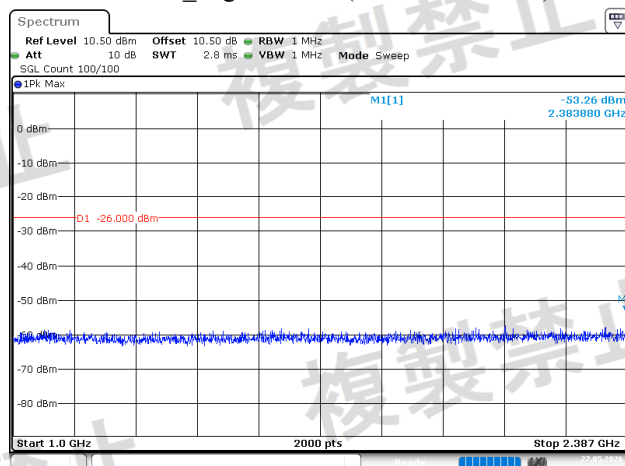
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 14:07:11

BLE 1M_High Channel(30MHz~1GHz)



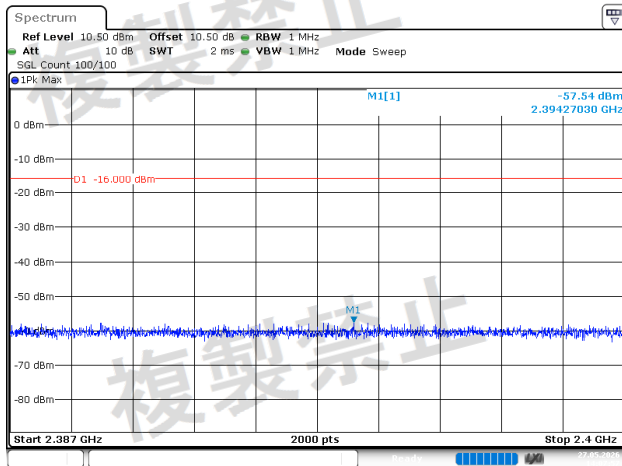
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 14:07:35

BLE 1M_High Channel(1GHz~2.387GHz)



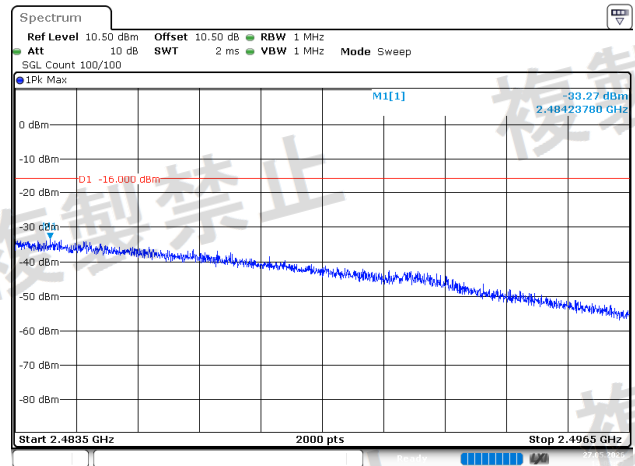
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 14:07:46

BLE 1M_High Channel(2.387GHz~2.4GHz)



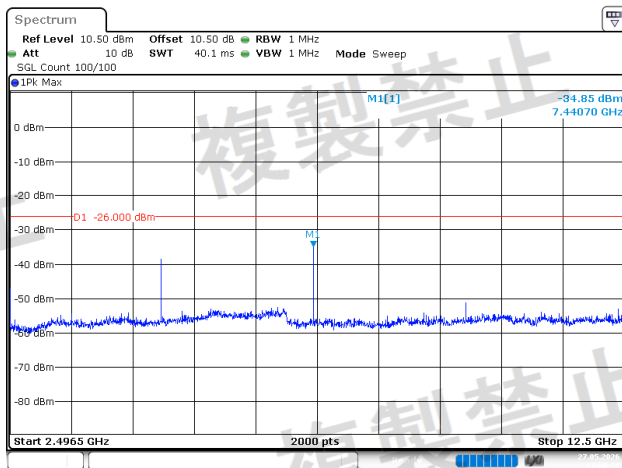
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 14:07:57

BLE 1M_High Channel(2.4835GHz~2.4965GHz)



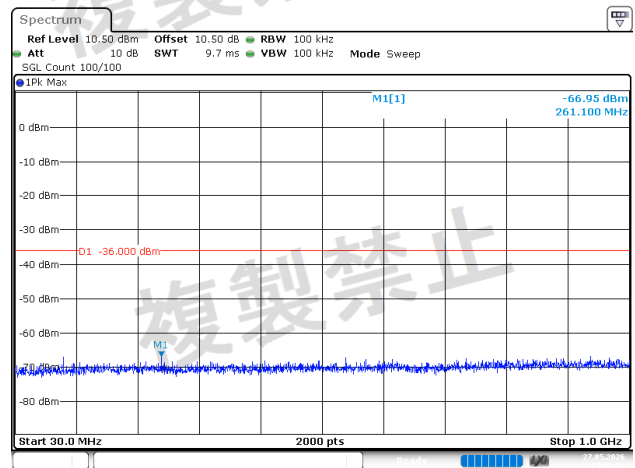
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 14:08:07

BLE 1M_High Channel(2.4965GHz~12.5GHz)



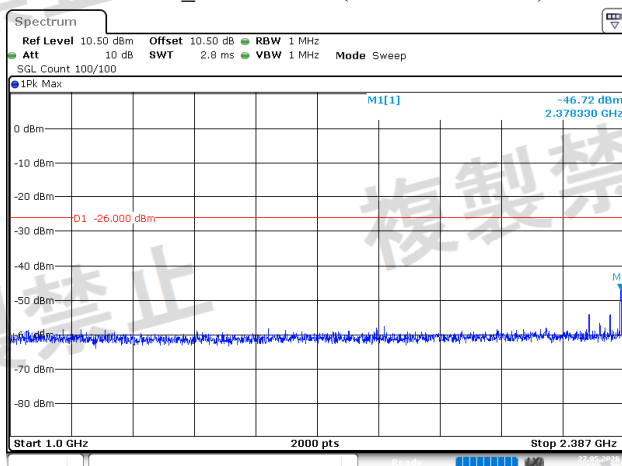
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Date: 27.MAY.2026 14:08:31

BLE 2M_Low Channel(30MHz~1GHz)



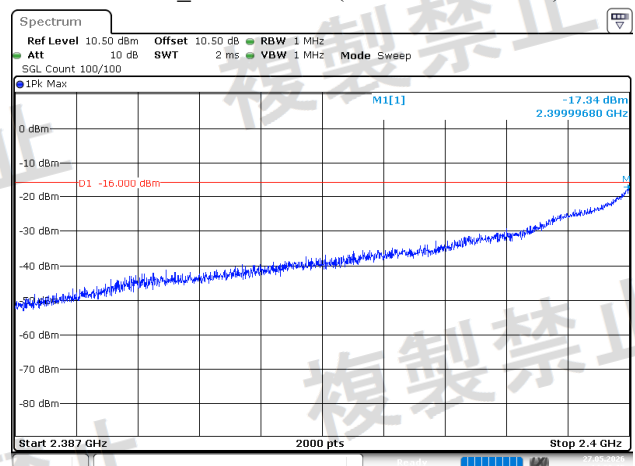
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Date: 27.MAY.2026 14:08:54

BLE 2M_Low Channel(1GHz~2.387GHz)



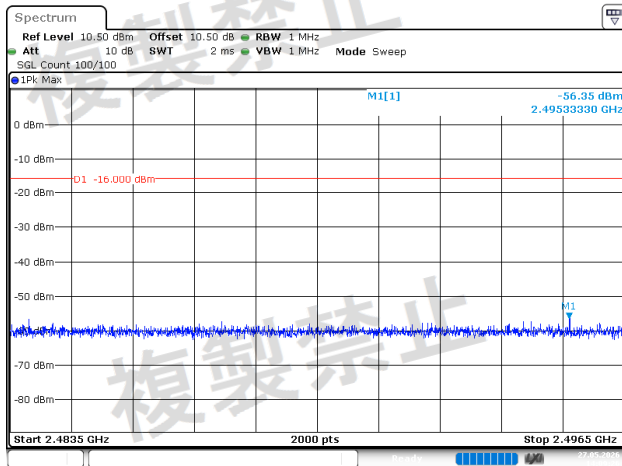
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Date: 27.MAY.2026 14:09:05

BLE 2M_Low Channel(2.387GHz~2.4GHz)



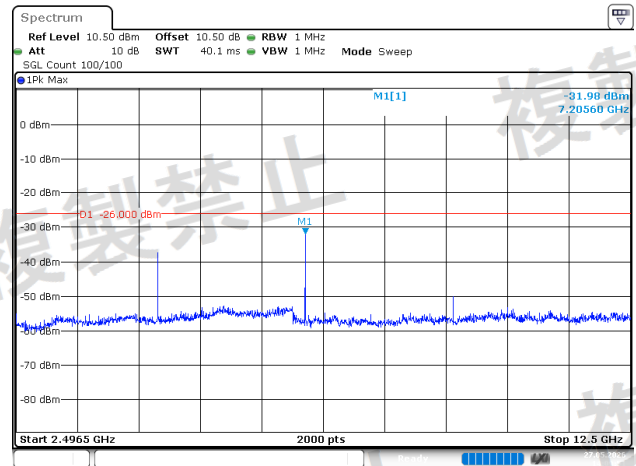
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Date: 27.MAY.2026 14:09:16

BLE 2M_Low Channel(2.4835GHz~2.4965GHz)



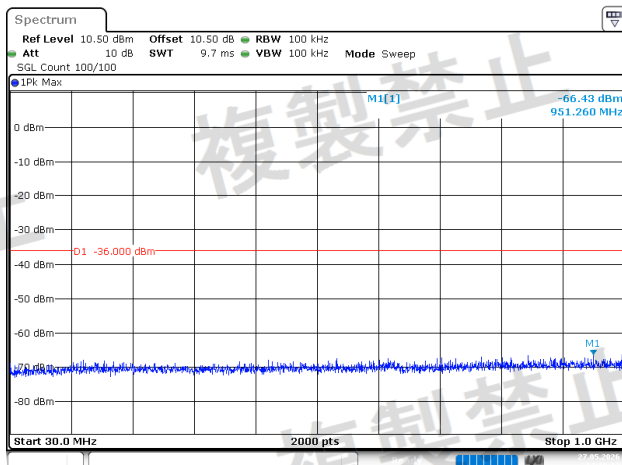
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Date: 27.MAY.2026 14:09:26

BLE 2M_Low Channel(2.4965GHz~12.5GHz)



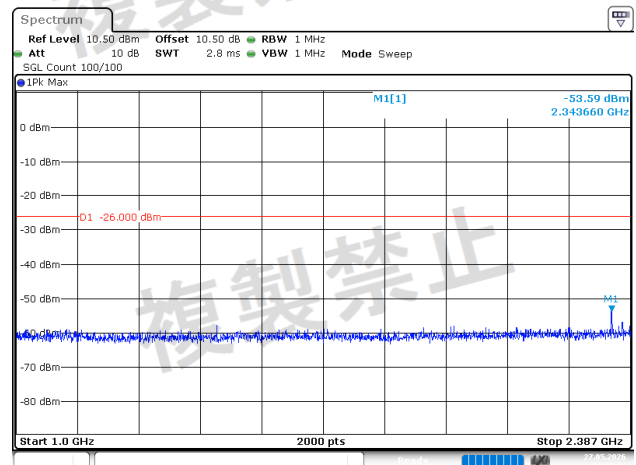
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Date: 27.MAY.2026 14:09:51

BLE 2M_Middle Channel(30MHz~1GHz)



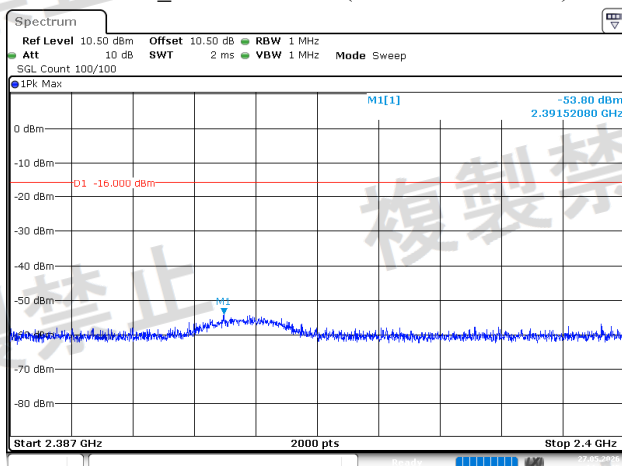
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Date: 27.MAY.2026 14:10:13

BLE 2M_Middle Channel(1GHz~2.387GHz)



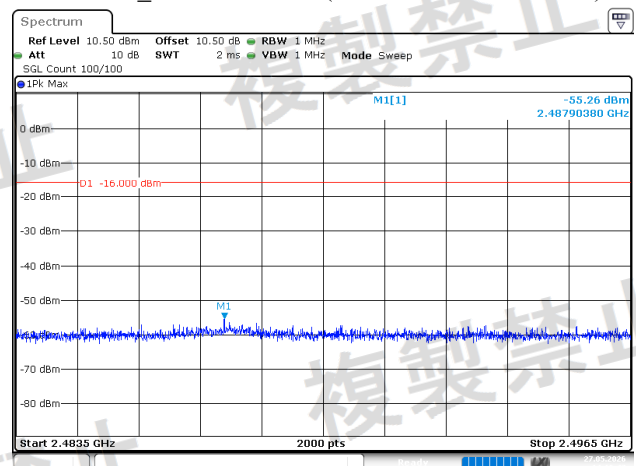
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Date: 27.MAY.2026 14:10:24

BLE 2M_Middle Channel(2.387GHz~2.4GHz)



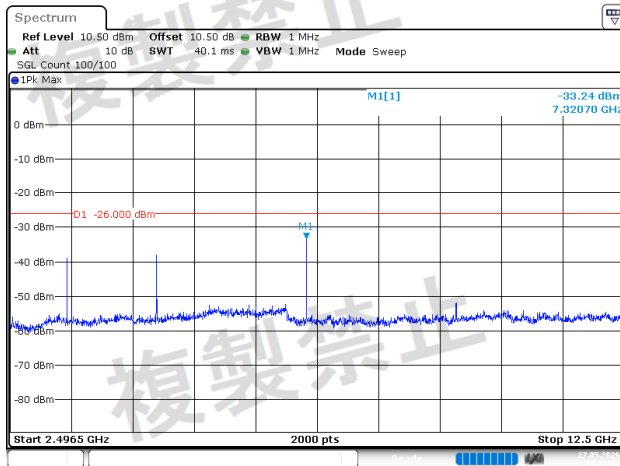
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Date: 27.MAY.2026 14:10:35

BLE 2M_Middle Channel(2.4835GHz~2.4965GHz)



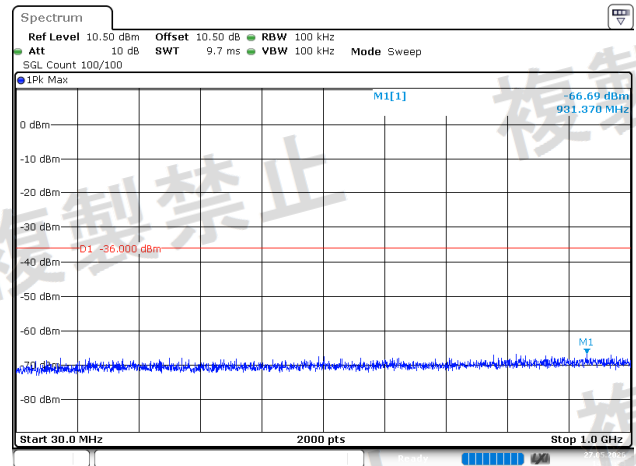
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BLE 2M_Middle Channel(2.4965GHz~12.5GHz)



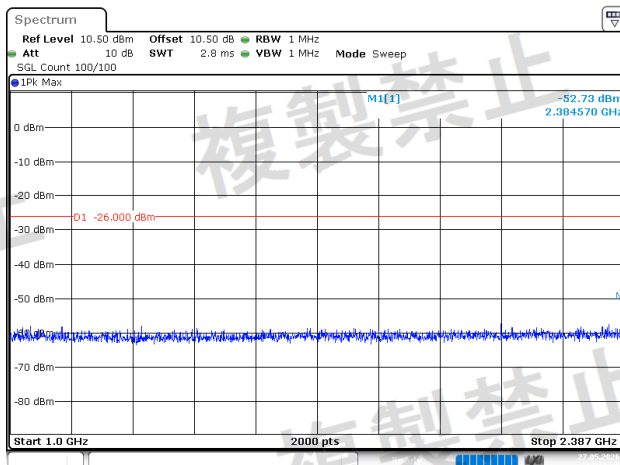
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Date: 27.MAY.2026 14:11:12

BLE 2M_High Channel(30MHz~1GHz)



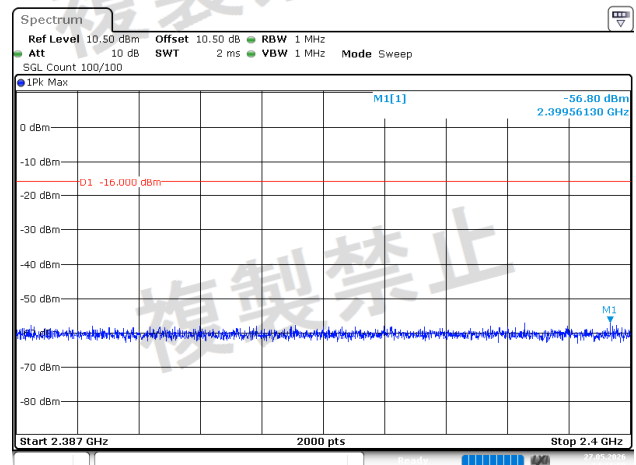
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Date: 27.MAY.2026 14:11:35

BLE 2M_High Channel(1GHz~2.387GHz)



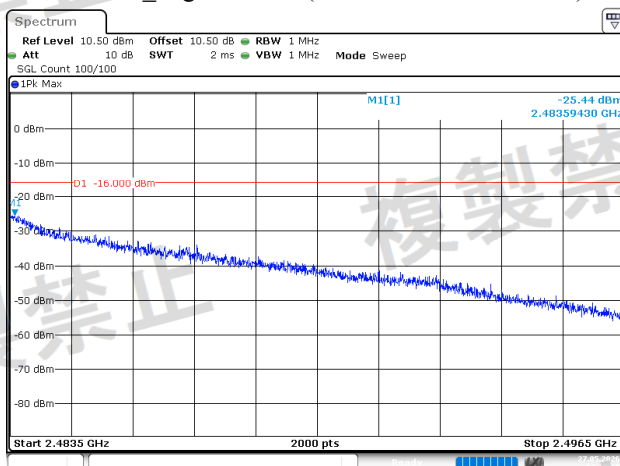
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Date: 27.MAY.2026 14:11:46

BLE 2M_High Channel(2.387GHz~2.4GHz)



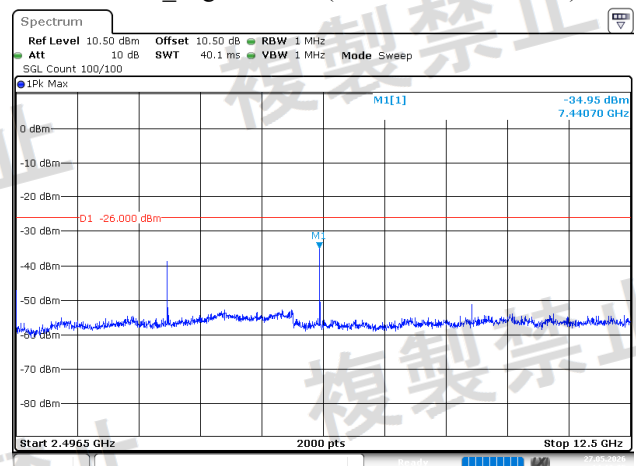
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Date: 27.MAY.2026 14:11:58

BLE 2M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 14:12:09

BLE 2M_High Channel(2.4965GHz~12.5GHz)



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 14:12:35

6.4 Antenna Output Power and Output Power Tolerance

Test Information:

Serial No.:	3KEN-1	Test Date:	2026/05/27
Test Site:	RF	Test Mode:	Transmitting
Tester:	Harper Shen	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	27.2	Relative Humidity: (%)	59	ATM Pressure: (kPa)	100.2
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Test Equipment List and Details:

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date	Calibration Agency	Calibration Method
Anritsu	Microwave Peak Power Sensor	MA24418A	12618	2025/06/11	2026/06/10	BACL Metrology	C
R&S	Coaxial Attenuator	10dB	F-08-EM512	2026/03/30	2027/03/29	BACL(DG)	D
All-sun	Clamp Meter	EM305A	8348897	2025/8/18	2026/8/17	BACL Metrology	C
Emerson	DC Power Supply	ONU4820	21021303532095 0100A0	N/A	N/A	N/A	N/A

* Statement of Traceability: Bay Area Compliance Laboratories Corp. (Dongguan) attests that all calibrations have been performed, traceable to National Primary Standards and International System of Units (SI).

Note:

- A. Calibration conducted by the National Institute of Information and Communications Technology (NICT) (hereinafter referred to as "NICT") or a designated calibration agency under Article 102-18 paragraph (1).
- B. Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Law (Law No. 51 of 1992).
- C. Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated calibration agency under Article 102-18 paragraph (1).
- D. Calibration conducted by using measuring instruments and other equipment which shall have been given any of calibration, etc. listed above from a) to c).

Test Condition: NV

Mode	Antenna gain (dBi)	Declared power (mW)
BLE 1M	0.69	2.50
BLE 2M		2.50

Mode	Channel	Conducted power(dBm)	Antenna output power(mW)		Antenna output tolerance(%)		EIRP (dBm)		Verdict
			Result	Limit	Result	Limit	Result	Limit	
BLE 1M	Low	3.88	2.443	≤ 10	-2.28	≤ 20	4.57	≤ 12.14	Pass
	Middle	3.84	2.421		-3.16		4.53		Pass
	High	3.76	2.377		-4.92		4.45		Pass
BLE 2M	Low	3.52	2.249	≤ 10	-10.04	≤ 20	4.21	≤ 12.14	Pass
	Middle	3.52	2.249		-10.04		4.21		Pass
	High	3.36	2.168		-13.28		4.05		Pass

Test Condition: LV

Mode	Antenna gain (dBi)	Declared power (mW)
BLE 1M	0.69	2.50
BLE 2M		2.50

Mode	Channel	Conducted power(dBm)	Antenna output power(mW)		Antenna output tolerance(%)		EIRP (dBm)		Verdict
			Result	Limit	Result	Limit	Result	Limit	
BLE 1M	Low	3.79	2.393	≤ 10	-4.28	≤ 20	4.48	≤ 12.14	Pass
	Middle	3.79	2.393		-4.28		4.48		Pass
	High	3.64	2.312		-7.52		4.33		Pass
BLE 2M	Low	3.49	2.234	≤ 10	-10.64	≤ 20	4.18	≤ 12.14	Pass
	Middle	3.47	2.223		-11.08		4.16		Pass
	High	3.22	2.099		-16.04		3.91		Pass

Test Condition: HV

Mode	Antenna gain (dBi)	Declared power (mW)
BLE 1M	0.69	2.50
BLE 2M		2.50

Mode	Channel	Conducted power(dBm)	Antenna output power(mW)		Antenna output tolerance(%)		EIRP (dBm)		Verdict
			Result	Limit	Result	Limit	Result	Limit	
BLE 1M	Low	3.61	2.296	≤ 10	-8.16	≤ 20	4.30	≤ 12.14	Pass
	Middle	3.62	2.301		-7.96		4.31		Pass
	High	3.56	2.270		-9.20		4.25		Pass
BLE 2M	Low	3.19	2.084	≤ 10	-16.64	≤ 20	3.88	≤ 12.14	Pass
	Middle	3.33	2.153		-13.88		4.02		Pass
	High	3.32	2.148		-14.08		4.01		Pass

Note:

 $\text{Antenna output power(mW)} = 10^{\{\text{Conducted power(dBm)} / 10\}}$ $\text{Antenna output power tolerance(\%)} = (\text{Antenna output power} - \text{Declared power}) / \text{Declared power} * 100\%$ $\text{Antenna output power(dBm)} = 10 * \log_{10}\{\text{Antenna output power(mW)}\}$ $\text{EIRP(dBm)} = \text{Antenna output power(dBm)} + \text{Antenna gain.}$

6.5 Receiver Spurious Emission and Unwanted Emission Intensity

Test Information:

Serial No.:	3KEN-1	Test Date:	2026/05/27
Test Site:	RF	Test Mode:	Receiving
Tester:	Harper Shen	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	27.2	Relative Humidity: (%)	59	ATM Pressure: (kPa)	100.2
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Test Equipment List and Details:

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date	Calibration Agency	Calibration Method
R&S	Spectrum Analyzer	FSV40	101589	2025/07/28	2026/07/27	BACL Metrology	C
R&S	Coaxial Attenuator	10dB	F-08-EM512	2026/03/30	2027/03/29	BACL(DG)	D
JD	Test Software	JD Auto Test System	V1.0	N/A	N/A	N/A	N/A
All-sun	Clamp Meter	EM305A	8348897	2025/8/18	2026/8/17	BACL Metrology	C
Emerson	DC Power Supply	ONU4820	210213035320950100A0	N/A	N/A	N/A	N/A

* Statement of Traceability: Bay Area Compliance Laboratories Corp. (Dongguan) attests that all calibrations have been performed, traceable to National Primary Standards and International System of Units (SI).

Note:

- Calibration conducted by the National Institute of Information and Communications Technology (NICT) (hereinafter referred to as "NICT") or a designated calibration agency under Article 102-18 paragraph (1).
- Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Law (Law No. 51 of 1992).
- Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated calibration agency under Article 102-18 paragraph (1).
- Calibration conducted by using measuring instruments and other equipment which shall have been given any of calibration, etc. listed above from a) to c).

Test Condition: NV

Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start (MHz)	Stop (MHz)					
BLE 1M	Low	Band I (100kHz)	30	1000	878.58	-76.84	0.021	4	Pass
		Band II (1MHz)	1000	12500	6891.74	-63.00	0.501	20	Pass
	Middle	Band I (100kHz)	30	1000	936.101	-76.78	0.021	4	Pass
		Band II (1MHz)	1000	12500	6899.21	-62.43	0.571	20	Pass
	High	Band I (100kHz)	30	1000	853.797	-76.96	0.020	4	Pass
		Band II (1MHz)	1000	12500	6005.66	-62.56	0.555	20	Pass
BLE 2M	Low	Band I (100kHz)	30	1000	632.879	-76.98	0.020	4	Pass
		Band II (1MHz)	1000	12500	5849.26	-62.38	0.578	20	Pass
	Middle	Band I (100kHz)	30	1000	833.766	-76.70	0.021	4	Pass
		Band II (1MHz)	1000	12500	6968.79	-62.87	0.516	20	Pass
	High	Band I (100kHz)	30	1000	823.048	-77.49	0.018	4	Pass
		Band II (1MHz)	1000	12500	5771.64	-62.64	0.545	20	Pass

Test Condition: LV

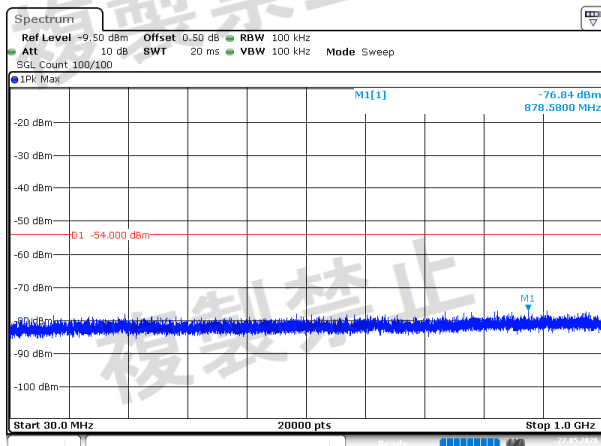
Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start (MHz)	Stop (MHz)					
BLE 1M	Low	Band I (100kHz)	30	1000	819.119	-75.90	0.026	4	Pass
		Band II (1MHz)	1000	12500	5807.86	-61.71	0.675	20	Pass
	Middle	Band I (100kHz)	30	1000	749.231	-76.84	0.021	4	Pass
		Band II (1MHz)	1000	12500	6972.81	-61.93	0.641	20	Pass
	High	Band I (100kHz)	30	1000	980.527	-76.26	0.024	4	Pass
		Band II (1MHz)	1000	12500	6976.84	-62.79	0.526	20	Pass
BLE 2M	Low	Band I (100kHz)	30	1000	906.759	-77.10	0.019	4	Pass
		Band II (1MHz)	1000	12500	5932.64	-62.28	0.592	20	Pass
	Middle	Band I (100kHz)	30	1000	877.998	-76.51	0.022	4	Pass
		Band II (1MHz)	1000	12500	5864.79	-62.08	0.619	20	Pass
	High	Band I (100kHz)	30	1000	941.582	-76.69	0.021	4	Pass
		Band II (1MHz)	1000	12500	6959.01	-62.58	0.552	20	Pass

Test Condition: HV

Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start (MHz)	Stop (MHz)					
BLE 1M	Low	Band I (100kHz)	30	1000	865.825	-77.02	0.020	4	Pass
		Band II (1MHz)	1000	12500	6821.01	-62.52	0.560	20	Pass
	Middle	Band I (100kHz)	30	1000	942.212	-76.80	0.021	4	Pass
		Band II (1MHz)	1000	12500	6727.86	-62.24	0.597	20	Pass
	High	Band I (100kHz)	30	1000	826.152	-77.15	0.019	4	Pass
		Band II (1MHz)	1000	12500	5841.21	-62.77	0.528	20	Pass
BLE 2M	Low	Band I (100kHz)	30	1000	795.112	-76.74	0.021	4	Pass
		Band II (1MHz)	1000	12500	6706.01	-62.54	0.557	20	Pass
	Middle	Band I (100kHz)	30	1000	972.913	-77.31	0.019	4	Pass
		Band II (1MHz)	1000	12500	6992.36	-62.88	0.515	20	Pass
	High	Band I (100kHz)	30	1000	835.076	-76.40	0.023	4	Pass
		Band II (1MHz)	1000	12500	5696.31	-62.47	0.566	20	Pass

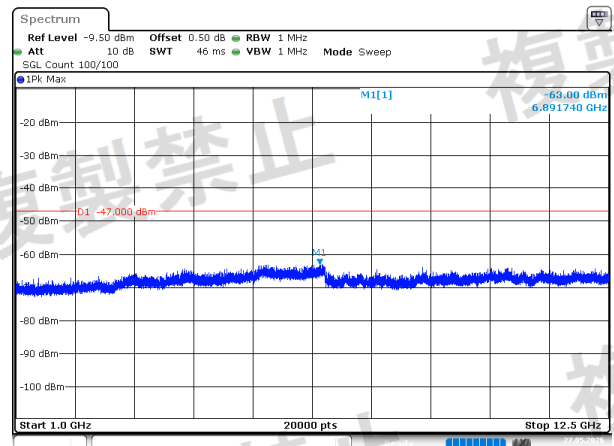
Test Condition: NV

BLE 1M_Low Channel(30MHz~1GHz)



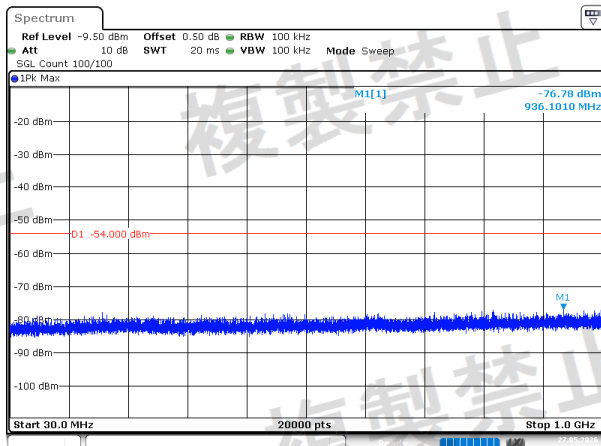
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Date: 27.MAY.2026 11:51:42

BLE 1M_Low Channel(1GHz~12.5GHz)



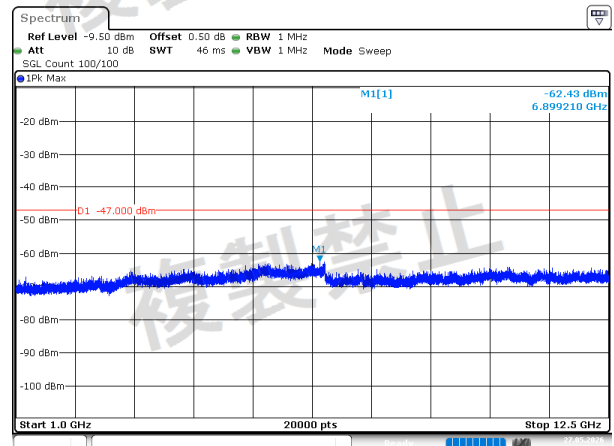
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Date: 27.MAY.2026 11:52:07

BLE 1M_Middle Channel(30MHz~1GHz)



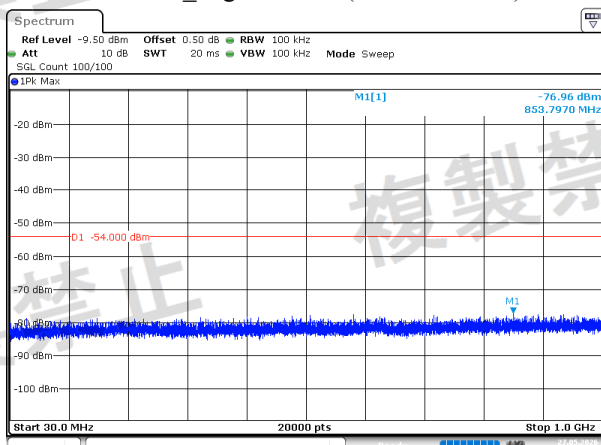
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Date: 27.MAY.2026 11:53:04

BLE 1M_Middle Channel(1GHz~12.5GHz)



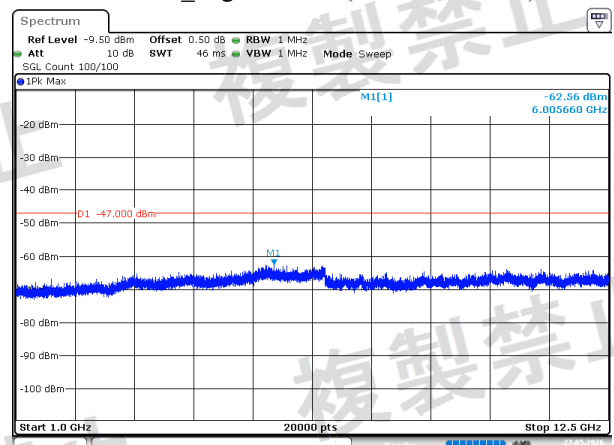
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BLE 1M_High Channel(30MHz~1GHz)



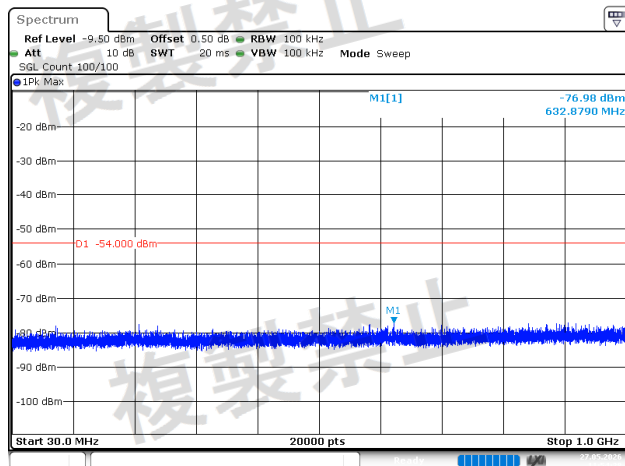
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BLE 1M_High Channel(1GHz~12.5GHz)



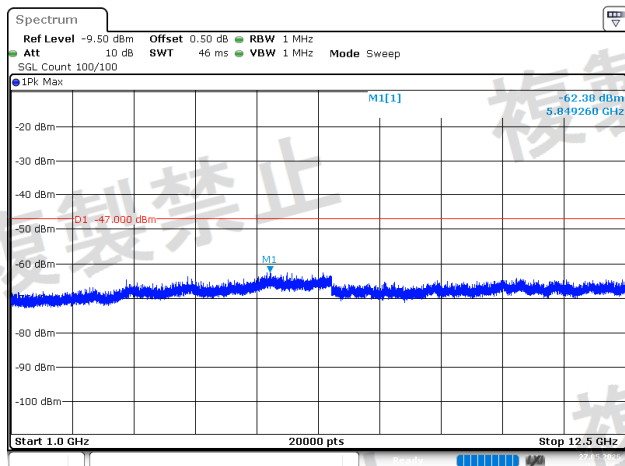
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Date: 27.MAY.2026 11:54:12

BLE 2M_Low Channel(30MHz~1GHz)



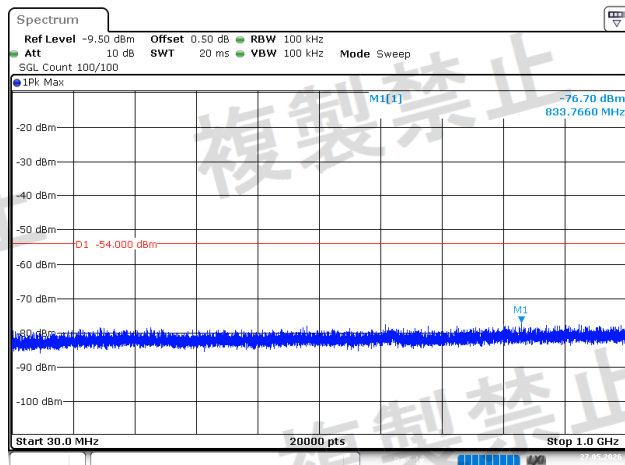
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Date: 27.MAY.2026 11:54:28

BLE 2M_Low Channel(1GHz~12.5GHz)



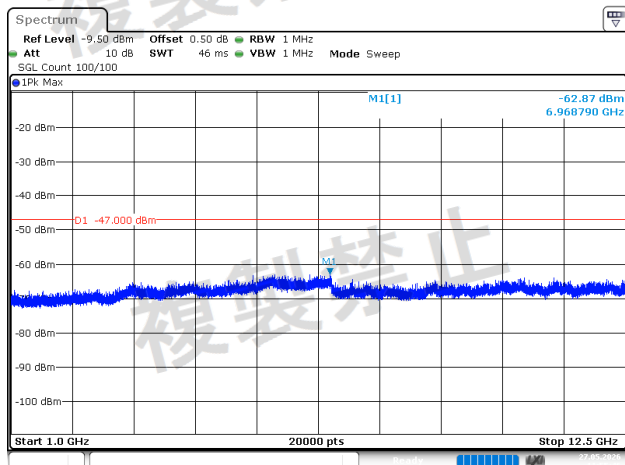
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:54:53

BLE 2M_Middle Channel(30MHz~1GHz)



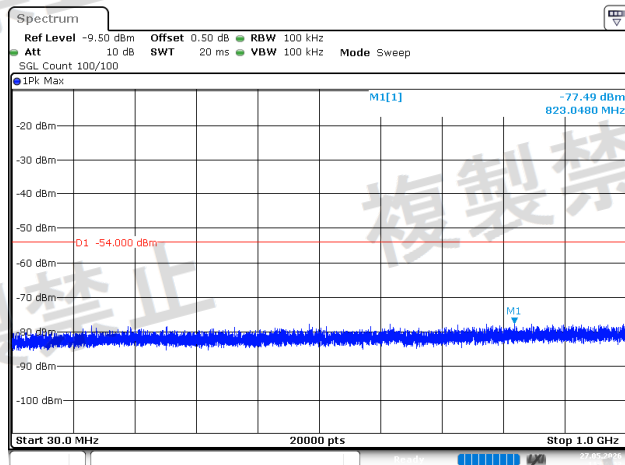
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Date: 27.MAY.2026 11:55:21

BLE 2M_Middle Channel(1GHz~12.5GHz)



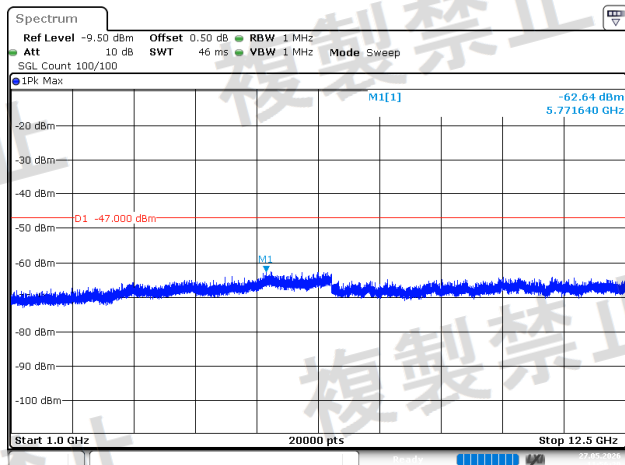
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Date: 27.MAY.2026 11:55:47

BLE 2M_High Channel(30MHz~1GHz)



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:56:04

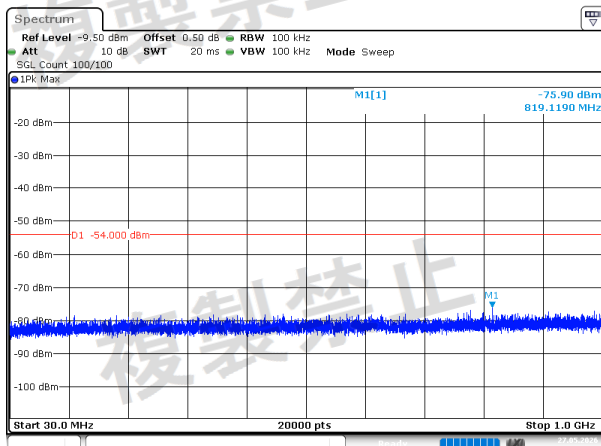
BLE 2M_High Channel(1GHz~12.5GHz)



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 11:56:29

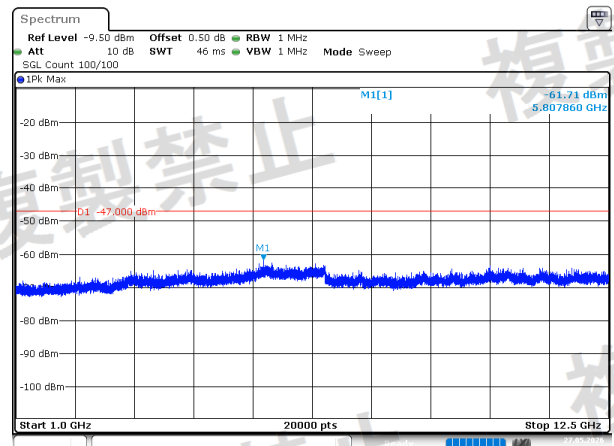
Test Condition: LV

BLE 1M_Low Channel(30MHz~1GHz)



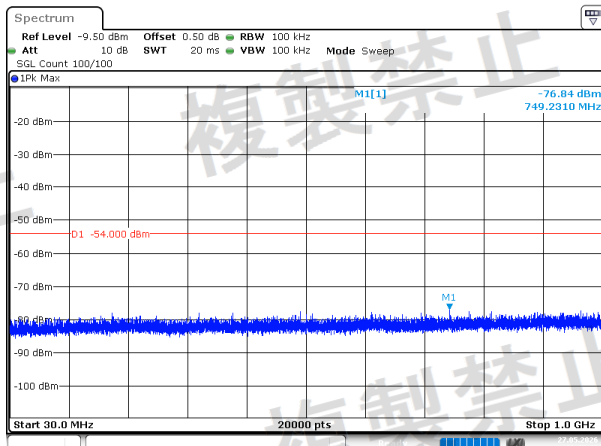
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BLE 1M_Low Channel(1GHz~12.5GHz)



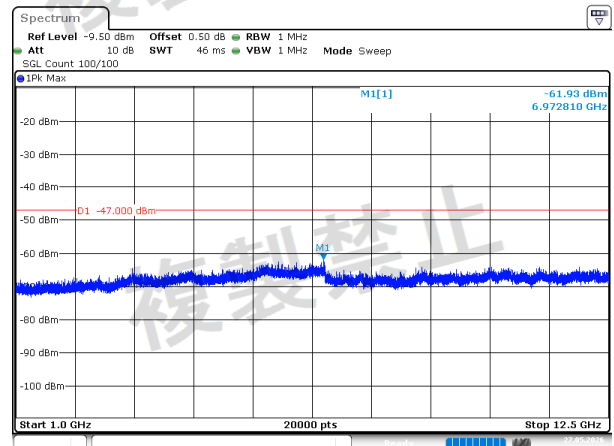
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Date: 27.MAY.2026 13:47:33

BLE 1M_Middle Channel(30MHz~1GHz)



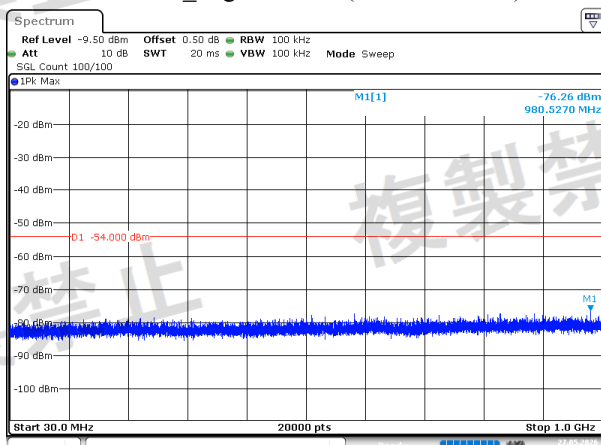
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Date: 27.MAY.2026 13:47:50

BLE 1M_Middle Channel(1GHz~12.5GHz)



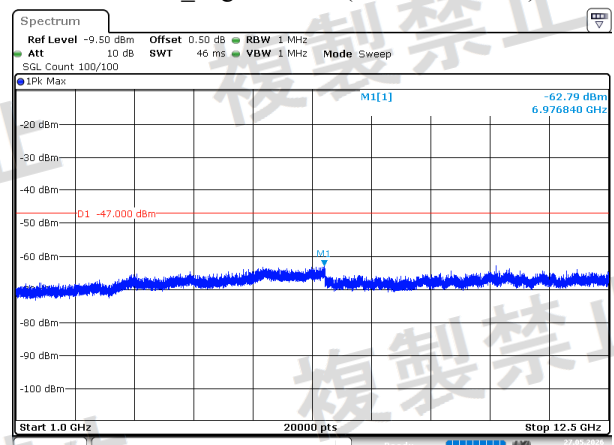
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Date: 27.MAY.2026 13:48:15

BLE 1M_High Channel(30MHz~1GHz)



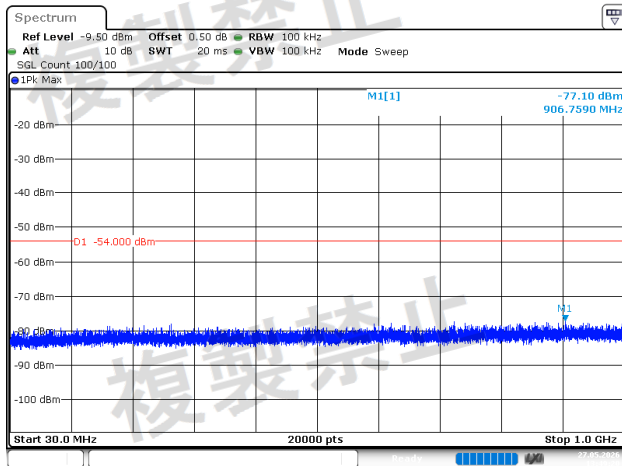
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:48:31

BLE 1M_High Channel(1GHz~12.5GHz)



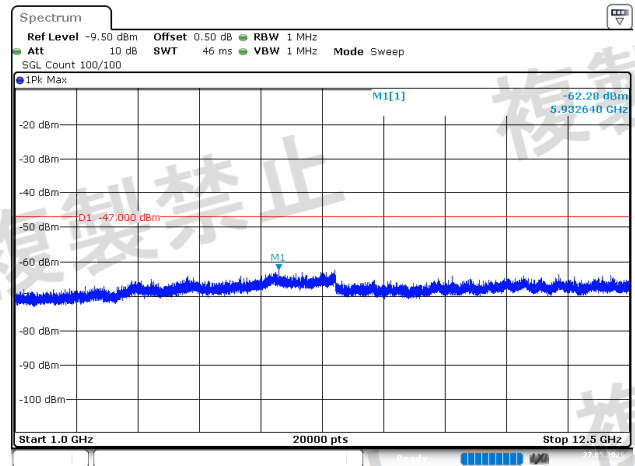
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:48:56

BLE 2M_Low Channel(30MHz~1GHz)



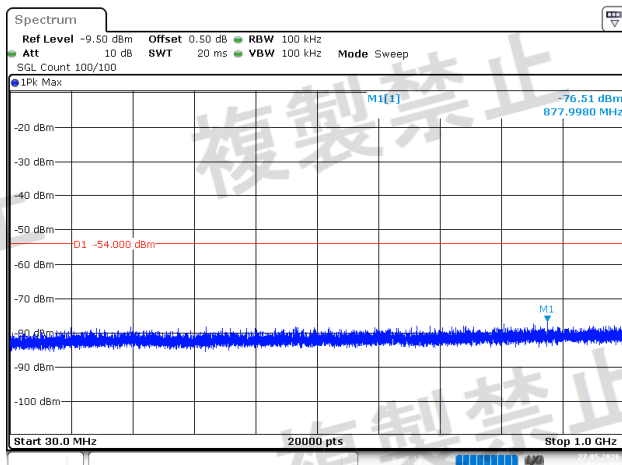
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:49:20

BLE 2M_Low Channel(1GHz~12.5GHz)



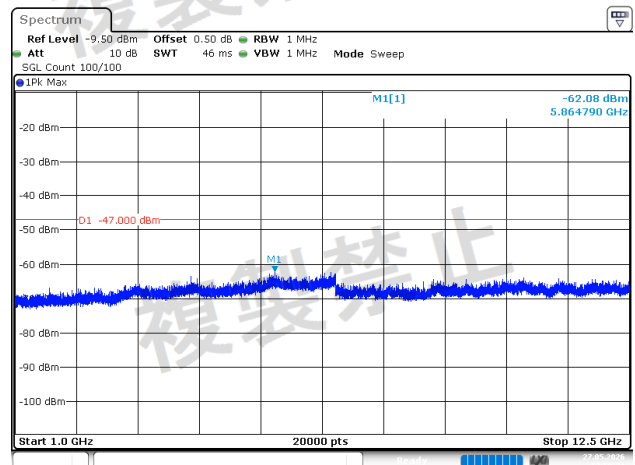
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:49:45

BLE 2M_Middle Channel(30MHz~1GHz)



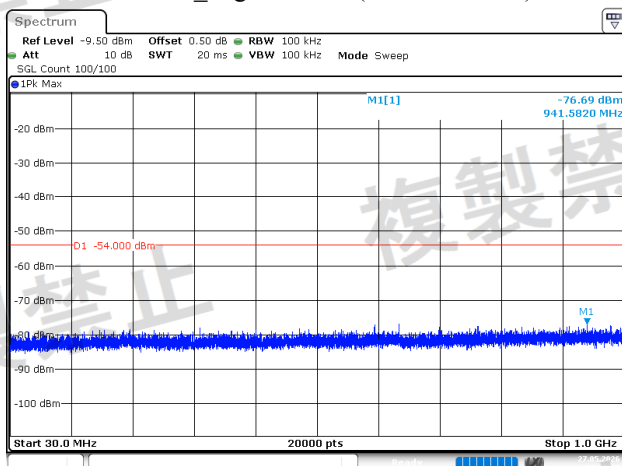
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:50:06

BLE 2M_Middle Channel(1GHz~12.5GHz)



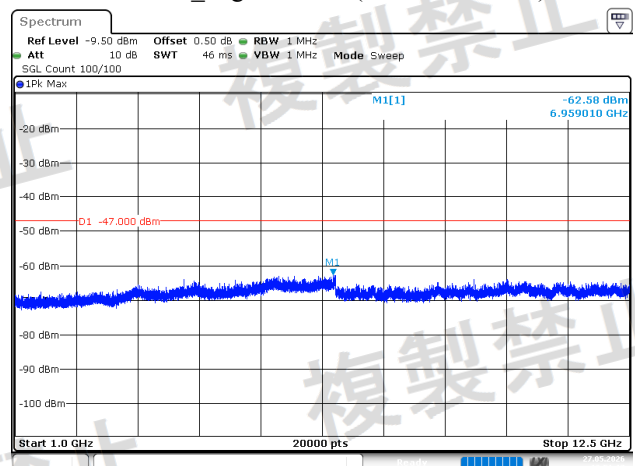
ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:50:31

BLE 2M_High Channel(30MHz~1GHz)



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:50:52

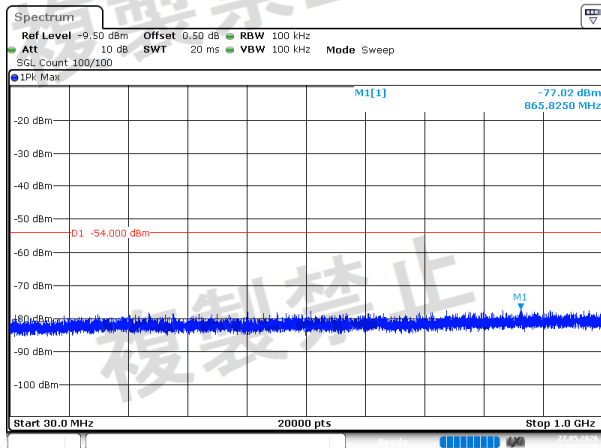
BLE 2M_High Channel(1GHz~12.5GHz)



ProjectNo.:2602S01344E-RF Tester:Harper Shen
Date: 27.MAY.2026 13:51:10

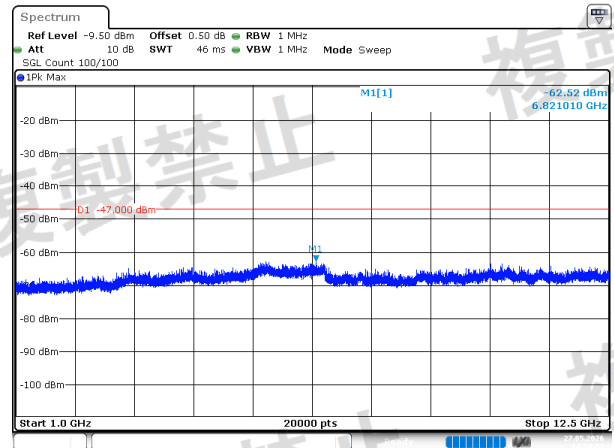
Test Condition: HV

BLE 1M_Low Channel(30MHz~1GHz)



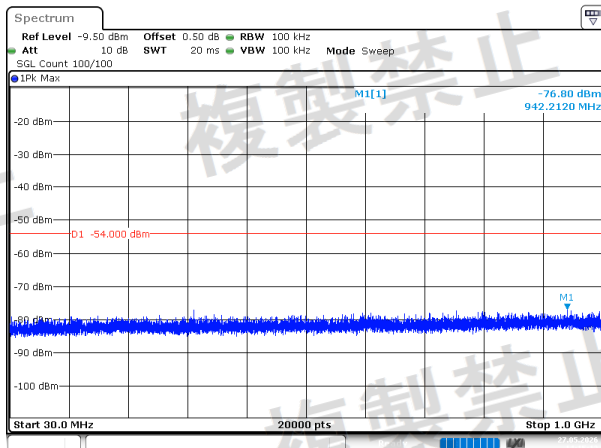
ProjectNo.:2602S01344E-RF Tester:Harper Shen
 Date: 27.MAY.2026 14:14:28

BLE 1M_Low Channel(1GHz~12.5GHz)



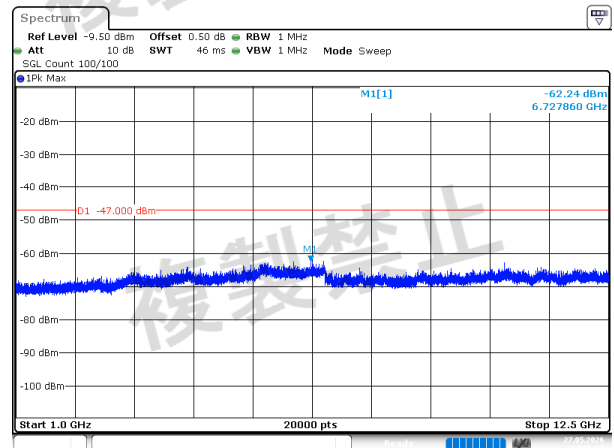
ProjectNo.:2602S01344E-RF Tester:Harper Shen
 Date: 27.MAY.2026 14:14:53

BLE 1M_Middle Channel(30MHz~1GHz)



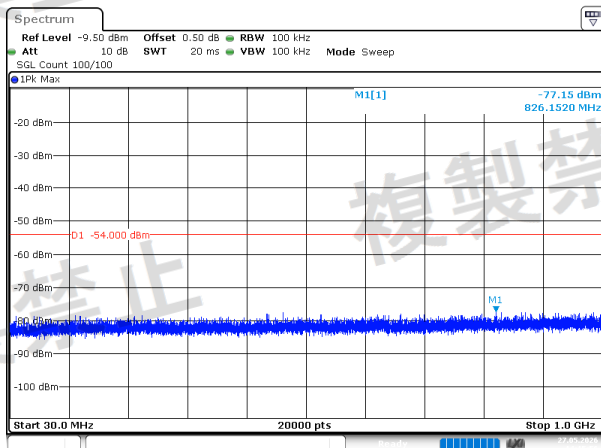
ProjectNo.:2602S01344E-RF Tester:Harper Shen
 Date: 27.MAY.2026 14:15:13

BLE 1M_Middle Channel(1GHz~12.5GHz)



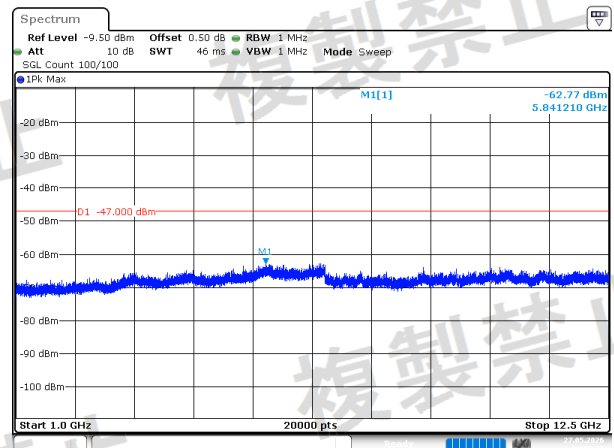
ProjectNo.:2602S01344E-RF Tester:Harper Shen
 Date: 27.MAY.2026 14:15:39

BLE 1M_High Channel(30MHz~1GHz)



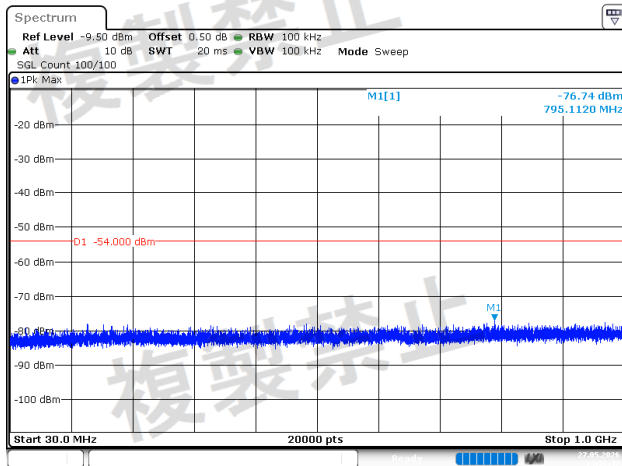
ProjectNo.:2602S01344E-RF Tester:Harper Shen
 Date: 27.MAY.2026 14:15:56

BLE 1M_High Channel(1GHz~12.5GHz)

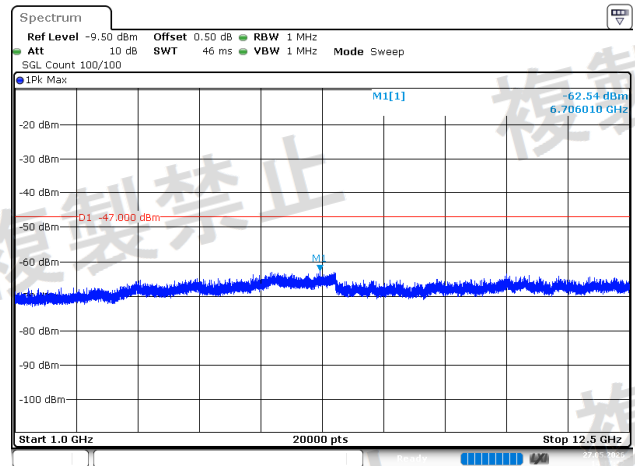


ProjectNo.:2602S01344E-RF Tester:Harper Shen
 Date: 27.MAY.2026 14:16:21

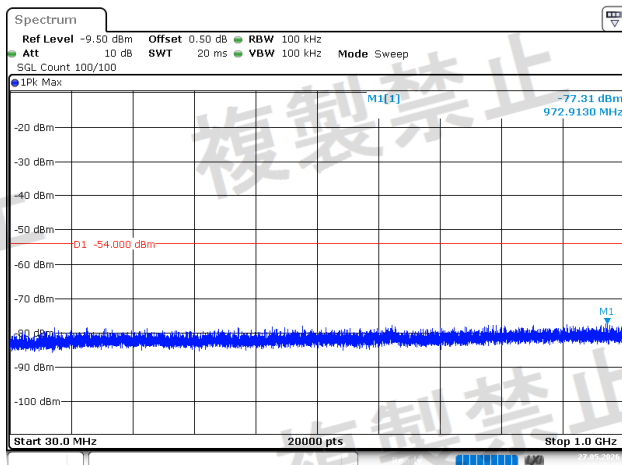
BLE 2M_Low Channel(30MHz~1GHz)



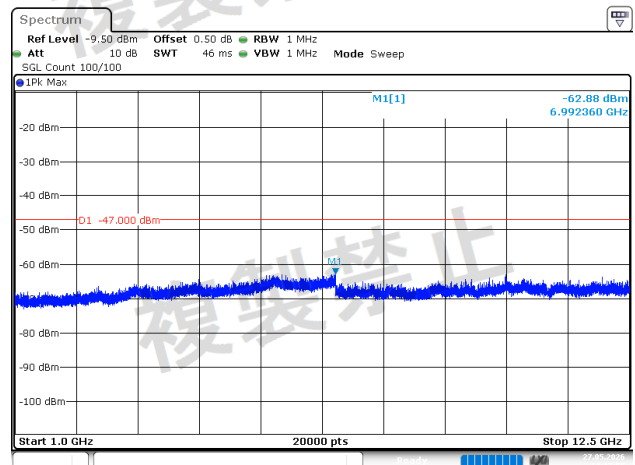
BLE 2M_Low Channel(1GHz~12.5GHz)



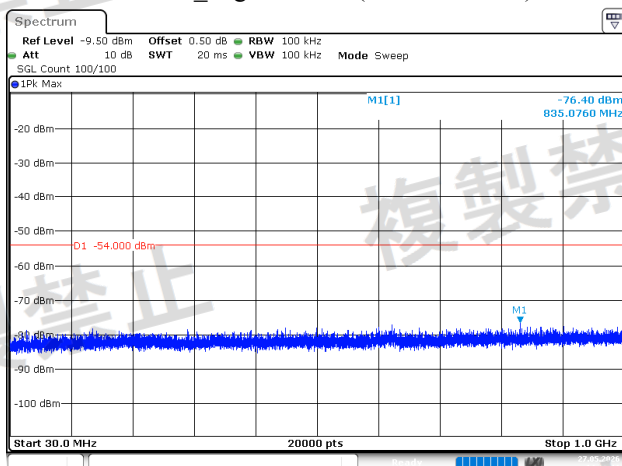
BLE 2M_Middle Channel(30MHz~1GHz)



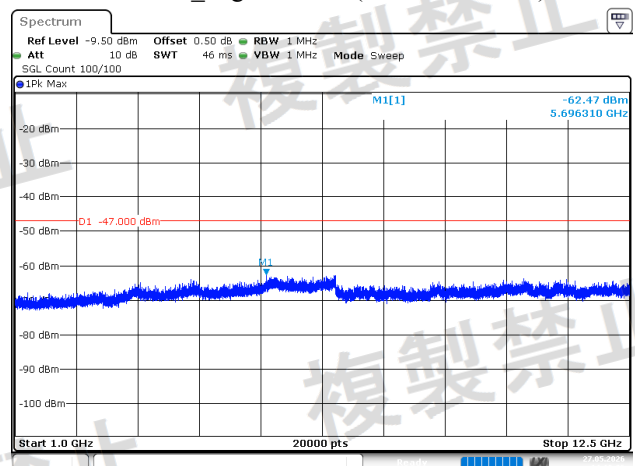
BLE 2M_Middle Channel(1GHz~12.5GHz)



BLE 2M_High Channel(30MHz~1GHz)



BLE 2M_High Channel(1GHz~12.5GHz)



6.6 Interference Prevention Function

Test Information:

Serial No.:	3KEN-1	Test Date:	2026/05/27
Test Site:	RF	Test Mode:	Communicating
Tester:	Harper Shen	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	27.2	Relative Humidity: (%)	59	ATM Pressure: (kPa)	100.2
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Test Equipment List and Details:

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date	Calibration Agency	Calibration Method
JD	Test Software	JD Auto Test System	V1.0	N/A	N/A	/	/
R&S	Spectrum Analyzer	FSV40	101589	2026/3/28	2027/3/27	BACL Metrology	C
Anritsu	Microwave Peak Power Sensor	MA24418A	12618	2025/6/11	2026/6/10	BACL Metrology	C
TDK-Lambda	DC Power Supply	Z+60-14	F-08-EM038-1	N/A	N/A	N/A	N/A
HUBER+SUHNER	Coaxial Attenuator	6610_SMA-50-1	0064	2026/3/30	2027/3/29	BACL(DG)	D
R&S	Coaxial Attenuator	10dB	F-08-EM512	2026/3/30	2027/3/29	BACL(DG)	D
All-sun	Clamp Meter	EM305A	8348897	2025/8/18	2026/8/17	BACL Metrology	C

* Statement of Traceability: Bay Area Compliance Laboratories Corp. (Dongguan) attests that all calibrations have been performed, traceable to National Primary Standards and International System of Units (SI).

Note:

- Calibration conducted by the National Institute of Information and Communications Technology (NICT) (hereinafter referred to as "NICT") or a designated calibration agency under Article 102-18 paragraph (1).
- Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Law (Law No. 51 of 1992).
- Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated calibration agency under Article 102-18 paragraph (1).
- Calibration conducted by using measuring instruments and other equipment which shall have been given any of calibration, etc. listed above from a) to c).

Item	Result	Requirement	Verdict
Methodology to transmit ID Code:	Automatically	Automatically	Compliant
Methodology to receive ID Code:	Automatically	Automatically	Compliant
Identification Codes (ID Codes):	9C:06:6E:18:08:53	/	/
Bits of ID Codes:	48 bits	48 bits or more	Compliant

Test Result: Good

7 - CONSTRUCTION PROTECTION CONFIRMATION

7.1 Requirements

The high-frequency section and modulation section of the radio equipment except for the antenna system shall not be capable of being opened easily.

7.2 Confirmation Result

The RF part (include antenna) covered by EUT case with screws, it can't be opened easily. Please refer the EUT photo.

8 - EXHIBIT A – EUT PHOTOGRAPHS

Please refer to the attachment 2602S01344E-RF-EXP EUT External photos and 2602S01344E-RF-INP EUT Internal photos.

9 - EXHIBIT B – TEST SETUP PHOTOGRAPHS

Please refer to the attachment 2602S01344E-RF-07-TSP Test Setup Photos.

****END OF REPORT****